

# 16-BIT, 500-KSPS, SERIAL INTERFACE MICROPOWER, MINIATURE, SAR ANALOG-TO-DIGITAL CONVERTER

Check for Samples: [ADS8318](#)

## FEATURES

- 500-kHz Sample Rate
- 16-Bit Resolution
- Zero Latency at Full Speed
- Unipolar, Differential Input, Range:  $-V_{ref}$  to  $V_{ref}$
- SPI Compatible Serial Interface with Daisy Chain Option
- Excellent Performance:
  - 95.2dB SNR Typ at 10-kHz I/P
  - -108dB THD Typ at 10-kHz I/P
  - $\pm 1.0$  LSB Max INL
  - $\pm 0.75$  LSB Max DNL
- Low Power Dissipation: 18 mW Typ at 500 KSPS
- Power Scales Linearly with Speed: 3.6 mW/100 KSPS
- Power Dissipation During Power-Down State: 0.25  $\mu$ W Typ
- 10-Pin MSOP and SON Packages

## APPLICATIONS

- Battery Powered Equipments
- Data Acquisition Systems
- Instrumentation and Process Control
- Medical Electronics
- Optical Networking

## DESCRIPTION

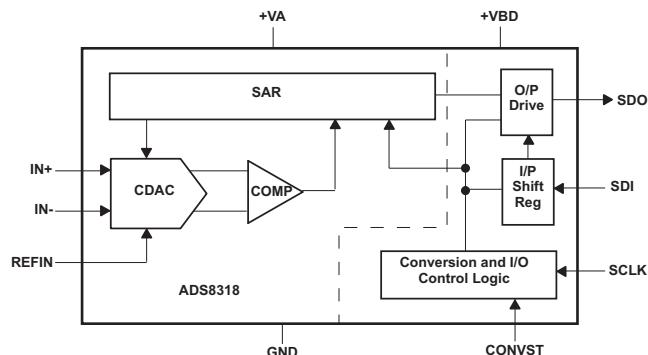
The ADS8318 is a 16-bit, 500-KSPS analog-to-digital converter. It operates with a 2.048-V to 5.5-V external reference. The device includes a capacitor based, SAR A/D converter with inherent sample and hold.

The device includes a 50-MHz SPI compatible serial interface. The interface is designed to support daisy chaining or cascading of multiple devices. Also a *Busy Indicator* makes it easy to synchronize with the digital host.

The ADS8318 unipolar differential input range supports a differential input swing of  $-V_{ref}$  to  $+V_{ref}$  with a common-mode of  $+V_{ref}/2$ .

Device operation is optimized for very low power operation, and the power consumption directly scales with speed. This feature makes it attractive for lower speed applications.

It is available in 10-pin MSOP and SON packages.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

 This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

 ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### ORDERING INFORMATION<sup>(1)</sup>

DEVICE	MAXIMUM INTEGRAL LINEARITY (LSB)	MAXIMUM DIFFERENTIAL LINEARITY (LSB)	NO MISSING CODES AT RESOLUTION (BIT)	PACKAGE TYPE	PACKAGE DESIGNATOR	TEMPERATURE RANGE	PACKAGE MARKING	ORDERING INFORMATION	TRANSPORT MEDIA QUANTITY
ADS8318I	$\pm 1.5$	$\pm 1$	16	10 Pin MSOP	DGS	−40°C to 85°C	CBC	ADS8318IDGST	250
				10 Pin SON	DRC		CBE	ADS8318IDGSR	2500
	$\pm 1.0$	$\pm 0.75$	16	10 Pin MSOP	DGS	−40°C to 85°C	CBC	ADS8318IDRCT	250
				10 Pin SON	DRC		CBE	ADS8318IDRCR	2500

(1) For the most current specifications and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at [www.ti.com](http://www.ti.com).

### ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range unless otherwise noted<sup>(1)</sup>

		VALUE	UNIT
+IN	−0.3 to +VA + 0.3	V	
	$\pm 130$	mA	
−IN	−0.3 to +VA + 0.3	V	
	$\pm 130$	mA	
+VA to AGND	−0.3 to 7	V	
+VBD to BDGND	−0.3 to 7	V	
Digital input voltage to GND	−0.3 to +VBD + 0.3	V	
Digital output to GND	−0.3 to +VBD + 0.3	V	
T <sub>A</sub> Operating free-air temperature range	−40 to 85	°C	
T <sub>stg</sub> Storage temperature range	−65 to 150	°C	
Junction temperature (T <sub>J</sub> max)	150	°C	
MSOP package	Power dissipation	$(T_J\text{Max} - T_A)/\theta_{JA}$	°C
	$\theta_{JA}$ thermal impedance	180	°C/W
Maximum MSOP reflow temperature	ADS8318 is rated to MSL2 260°C per the JSTD-020 specification		
SON package	Power dissipation	$(T_J\text{Max} - T_A)/\theta_{JA}$	
	$\theta_{JA}$ thermal impedance	70	°C/W
Maximum SON reflow temperature	ADS8318 is rated to MSL2 260°C per the JSTD-020 specification		

(1) Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## SPECIFICATIONS

$T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$ ,  $+\text{VA} = 5\text{ V}$ ,  $+\text{VBD} = 5\text{ V}$  to  $2.375\text{ V}$ ,  $V_{\text{ref}} = 4\text{ V}$ ,  $f_{\text{SAMPLE}} = 500\text{ kHz}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>ANALOG INPUT</b>						
Full-scale input span <sup>(1)</sup>		+IN – (–IN)	$-V_{\text{ref}}$	$V_{\text{ref}}$		V
Operating input range	+IN		– 0.1	$V_{\text{ref}} + 0.1$		
	–IN		– 0.1	$V_{\text{ref}} + 0.1$		
Input common-mode range			0	$V_{\text{ref}}/2$	$V_{\text{ref}}/2 + 0.1$	V
Input capacitance	+IN and -IN terminal to GND			59		pF
Input leakage current	During acquisition			1000		pA
<b>SYSTEM PERFORMANCE</b>						
Resolution				16		Bits
No missing codes				16		Bits
INL	Integral linearity <sup>(2)</sup>	ADS8318I ADS8318IB		–1.5	$\pm 0.65$	1.5
				–1	$\pm 0.65$	1
DNL	Differential linearity	ADS8318I ADS8318IB	At 16-bit level	–1	$\pm 0.4$	1
				–0.75	$\pm 0.4$	0.75
$E_O$	Offset error <sup>(4)</sup>			–1.5	$\pm 0.3$	1.5
$E_G$	Gain error			–0.03	$\pm 0.003$	0.03
CMRR	Common-mode rejection ratio	With common mode input signal = $200\text{ mV}_{\text{p-p}}$ at 500 kHz			78	dB
PSRR	Power supply rejection ratio	At FFF0h output code			80	dB
Transition noise					0.25	LSB
<b>SAMPLING DYNAMICS</b>						
$t_{\text{CONV}}$	Conversion time	+VBD = 5 V			1400	ns
		+VBD = 3 V			1400	
	Acquisition time	+VBD = 5 V		600		ns
		+VBD = 3 V		600		
Maximum throughput rate with or without latency					0.5	MHz
Aperture delay				2.5		ns
Aperture jitter, RMS				6		ps
Step response	Settling to 16-bit accuracy			600		ns
Overvoltage recovery				600		ns

(1) Ideal input span, does not include gain or offset error.

(2) This is endpoint INL, not best fit.

(3) LSB means least significant bit

(4) Measured relative to actual measured reference.

**SPECIFICATIONS (continued)**

$T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$ ,  $+VA = 5\text{ V}$ ,  $+VBD = 5\text{ V}$  to  $2.375\text{ V}$ ,  $V_{\text{ref}} = 4\text{ V}$ ,  $f_{\text{SAMPLE}} = 500\text{ kHz}$  (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
<b>DYNAMIC CHARACTERISTICS</b>							
THD	Total harmonic distortion <sup>(5)</sup>	$V_{\text{IN}} 0.4\text{ dB}$ below FS at 1 kHz, $V_{\text{ref}} = 5\text{ V}$		-114		dB	
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 10 kHz, $V_{\text{ref}} = 5\text{ V}$		-108			
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 100 kHz, $V_{\text{ref}} = 5\text{ V}$		-91.5			
SNR	Signal-to-noise ratio	$V_{\text{IN}} 0.4\text{ dB}$ below FS at 1 kHz, $V_{\text{ref}} = 5\text{ V}$		96		dB	
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 10 kHz, $V_{\text{ref}} = 5\text{ V}$		95.2			
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 100 kHz, $V_{\text{ref}} = 5\text{ V}$		92.5			
		ADS8318IB	$V_{\text{IN}} 0.4\text{ dB}$ below FS at 1 kHz, $V_{\text{ref}} = 5\text{ V}$	95.5			
SINAD	Signal-to-noise + distortion	$V_{\text{IN}} 0.4\text{ dB}$ below FS at 1 kHz, $V_{\text{ref}} = 5\text{ V}$		96		dB	
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 10 kHz, $V_{\text{ref}} = 5\text{ V}$		95			
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 100 kHz, $V_{\text{ref}} = 5\text{ V}$		89.5			
SFDR	Spurious free dynamic range	$V_{\text{IN}} 0.4\text{ dB}$ below FS at 1 kHz, $V_{\text{ref}} = 5\text{ V}$		116		dB	
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 10 kHz, $V_{\text{ref}} = 5\text{ V}$		109			
		$V_{\text{IN}} 0.4\text{ dB}$ below FS at 100 kHz, $V_{\text{ref}} = 5\text{ V}$		92			
-3dB Small signal bandwidth				15		MHz	
<b>EXTERNAL REFERENCE INPUT</b>							
$V_{\text{ref}}$	Input range		2.048	4.096	VDD+0.1	V	
	Reference input current <sup>(6)</sup>	During conversion		250		µA	
<b>POWER SUPPLY REQUIREMENTS</b>							
Power supply voltage	+VBD		2.375	3.3	5.5	V	
	+VA		4.5	5	5.5	V	
Supply current	+VA	500-kHz Sample rate		3.6	4.5	mA	
$P_{\text{VA}}$	Power dissipation		18	22.5		mW	
$IV_{\text{A}_{\text{pd}}}$	Device power-down current <sup>(7)</sup>		50	300		nA	
<b>LOGIC FAMILY CMOS</b>							
$V_{\text{IH}}$	Logic level	$I_{\text{IH}} = 5\text{ }\mu\text{A}$	$+(0.7 \times V_{\text{BD}})$		$+V_{\text{BD}}+0.3$	V	
		$I_{\text{IL}} = 5\text{ }\mu\text{A}$	-0.3		$+(0.3 \times V_{\text{BD}})$	V	
		$I_{\text{OH}} = 2$ TTL loads	$+V_{\text{BD}}-0.3$		$+V_{\text{BD}}$	V	
		$I_{\text{OL}} = 2$ TTL loads	0		0.4	V	
<b>TEMPERATURE RANGE</b>							
$T_A$	Operating free-air temperature		-40	85		°C	

(5) Calculated on the first nine harmonics of the input frequency

(6) Can vary  $\pm 20\%$

(7) Device automatically enters power-down state at the end of every conversion, and continues to be in power-down state as long as it is in acquisition phase.

## TIMING REQUIREMENTS

All specifications typical at  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ ,  $+\text{VA} = 5\text{ V}$ ,  $+\text{VBD} \geq 3.1\text{ V}$

PARAMETER	REF FIGURE	MIN	TYP	MAX	UNIT
<b>SAMPLING AND CONVERSION RELATED</b>					
$t_{\text{acq}}$	Acquisition time	600			ns
$t_{\text{cnv}}$	Conversion time		1400		ns
$t_{\text{cyc}}$	Time between conversions	2000			ns
$t_1$	Pulse duration, CONVST high	Figure 46, Figure 48	10		ns
$t_6$	Pulse duration, CONVST low	Figure 50, Figure 52, Figure 54	20		ns
<b>I/O RELATED</b>					
$t_{\text{clk}}$	SCLK Period	20			ns
$t_{\text{clkL}}$	SCLK Low time	8			ns
$t_{\text{clkH}}$	SCLK High time	8			ns
$t_2$	SCLK Falling edge to data remains valid	5			ns
$t_3$	SCLK Falling edge to next data valid delay		16		ns
$t_{\text{en}}$	Enable time, CONVST or SDI Low to MSB valid	Figure 46, Figure 50	15		ns
$t_{\text{dis}}$	Disable time, CONVST or SDI high or last SCLK falling edge to SDO 3-state ( $\bar{CS}$ mode)	Figure 46, Figure 48, Figure 50, Figure 52	12		ns
$t_4$	Setup time, SDI valid to CONVST rising edge	Figure 50, Figure 52	5		ns
$t_5$	Hold time, SDI valid from CONVST rising edge		5		ns
$t_7$	Setup time, SCLK valid to CONVST rising edge	Figure 54	5		ns
$t_8$	Hold time, SCLK valid from CONVST rising edge		5		ns

## TIMING REQUIREMENTS

All specifications typical at  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ ,  $+\text{VA} = 5\text{ V}$ ,  $+3.1\text{ V} > +\text{VBD} \geq 2.375\text{ V}$

PARAMETER	REF FIGURE	MIN	TYP	MAX	UNIT
<b>SAMPLING AND CONVERSION RELATED</b>					
$t_{\text{acq}}$	Acquisition time	600			ns
$t_{\text{cnv}}$	Conversion time		1400		ns
$t_{\text{cyc}}$	Time between conversions	2000			ns
$t_1$	Pulse width CONVST high	Figure 46, Figure 48	10		ns
$t_6$	Pulse width CONVST low	Figure 50, Figure 52, Figure 54	20		ns
<b>I/O RELATED</b>					
$t_{\text{clk}}$	SCLK period	30			ns
$t_{\text{clkL}}$	SCLK low time	13			ns
$t_{\text{clkH}}$	SCLK high time	13			ns
$t_2$	SCLK falling edge to data remains valid	5			ns
$t_3$	SCLK falling edge to next data valid delay		24		ns
$t_{\text{en}}$	CONVST or SDI low to MSB valid	Figure 46, Figure 50	22		ns
$t_{\text{dis}}$	CONVST or SDI high or last SCLK falling edge to SDO 3-state ( $\text{CS}$ mode)	Figure 46, Figure 48, Figure 50, Figure 52	15		ns
$t_4$	SDI valid setup time to CONVST rising edge	Figure 50, Figure 52	5		ns
$t_5$	SDI valid hold time from CONVST rising edge	5			ns
$t_7$	SCLK valid setup time to CONVST rising edge	Figure 54	5		ns
$t_8$	SCLK valid hold time from CONVST rising edge		5		ns

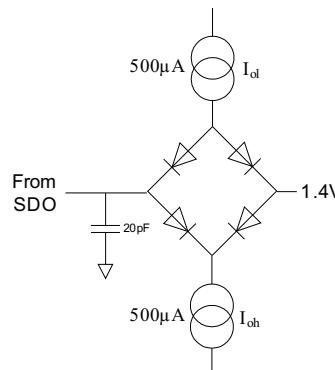


Figure 1. Load Circuit for Digital Interface Timing

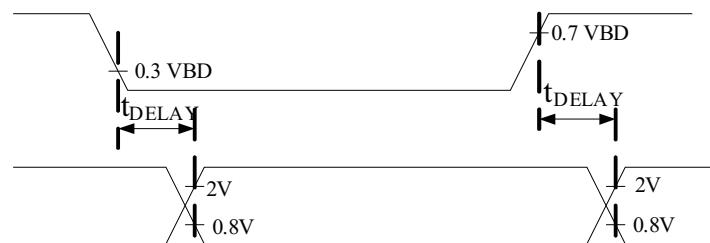


Figure 2. Voltage Levels for Timing

## PIN ASSIGNMENTS



## Terminal Functions

TERMINAL		I/O	DESCRIPTION
NO.	NAME		
<b>ANALOG PINS</b>			
1	REFIN	I	Reference (positive) input. Decouple with GND pin using 0.1- $\mu$ F bypass capacitor and 10- $\mu$ F storage capacitor.
3	+IN	I	Noninverting analog signal input
4	-IN	I	Inverting analog signal input
<b>I/O PINS</b>			
6	CONVST	I	Convert input. It also functions as the $\overline{CS}$ input in 3-wire interface mode. Refer to Description and Timing Diagrams sections for more details.
7	SDO	O	Serial data output.
8	SCLK	I	Serial I/O clock input. Data (on SDO o/p) is synchronized with this clock.
9	SDI	I	Serial data input. The SDI level at the start of a conversion selects the mode of operation such as $\overline{CS}$ or daisy chain mode. It also serves as the $\overline{CS}$ input in 4-wire interface mode. Refer to Description and Timing Diagrams sections for more details.
<b>POWER SUPPLY PINS</b>			
2	+VA	-	Analog power supply. Decoupled with GND pin.
5	GND	-	Device ground. Note this is a common ground pin for both analog power supply (+VA) and digital I/O supply (+VBD).
10	+VBD	-	Digital I/O power supply. Decouple with GND pin.

## TYPICAL CHARACTERISTICS

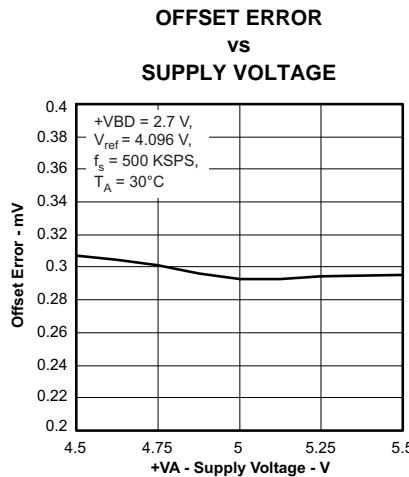


Figure 3.

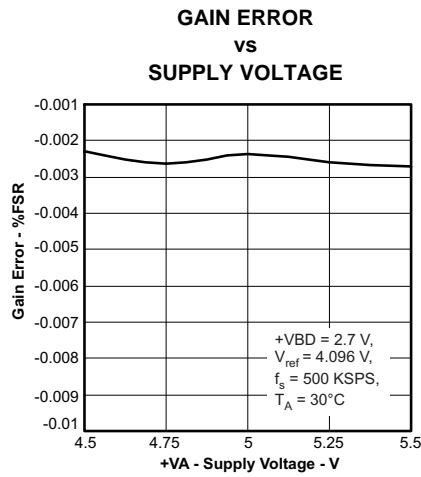


Figure 4.

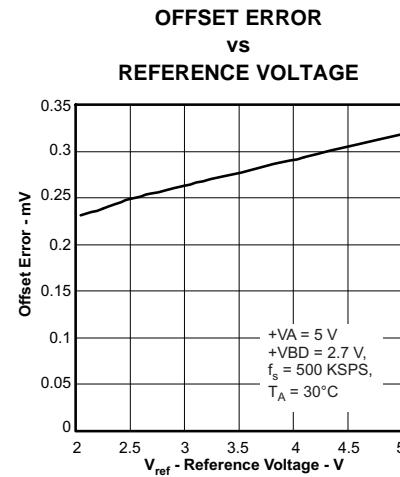


Figure 5.

## TYPICAL CHARACTERISTICS (continued)

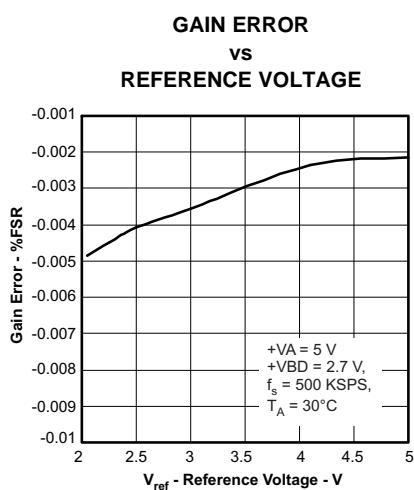


Figure 6.

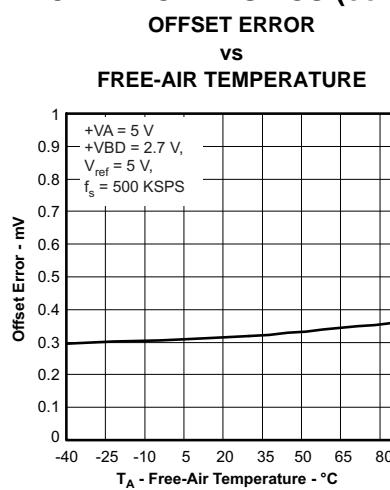


Figure 7.

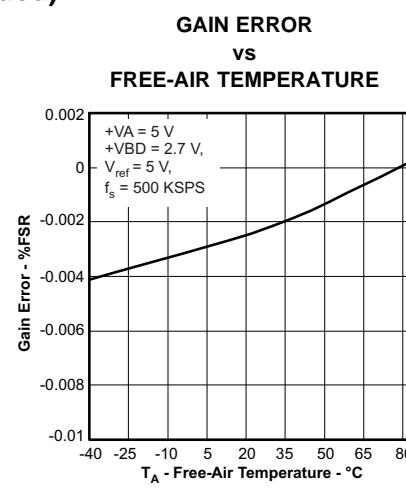


Figure 8.

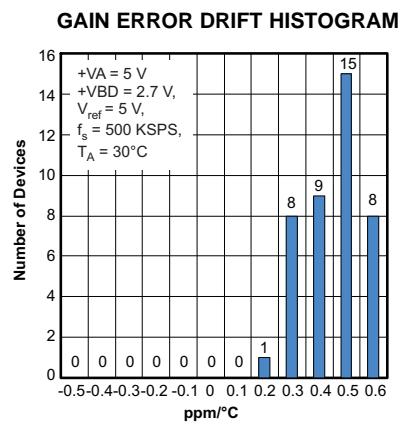


Figure 9.

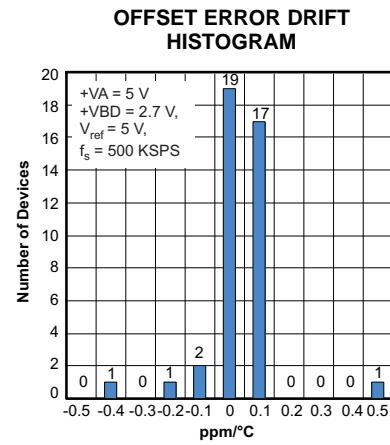


Figure 10.

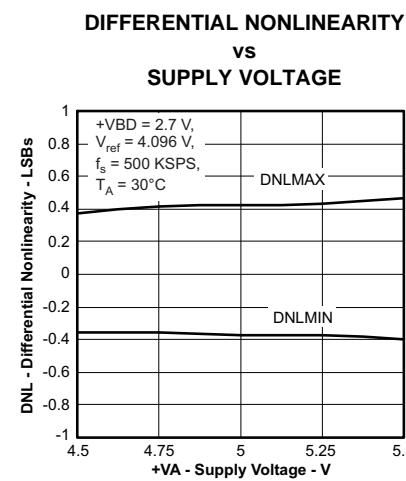


Figure 11.

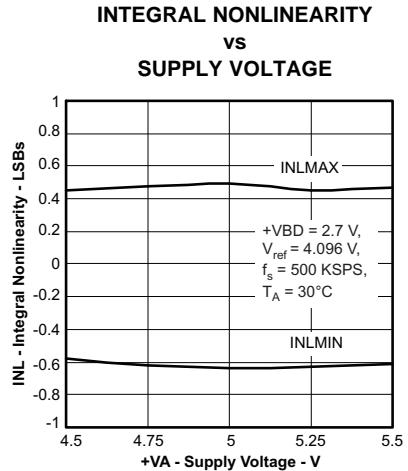


Figure 12.

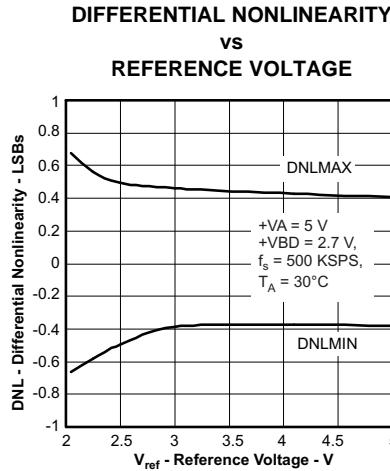


Figure 13.

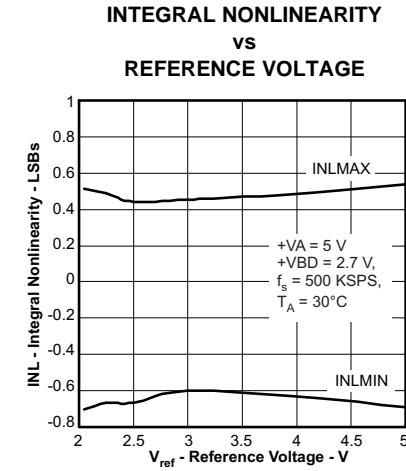
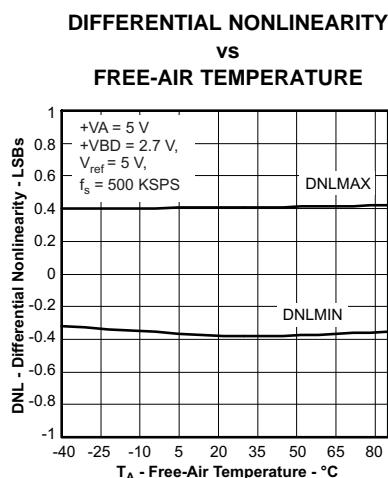
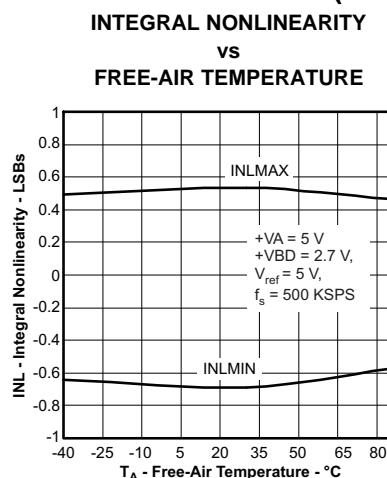
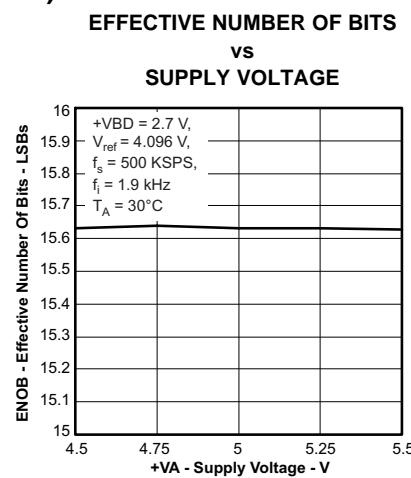
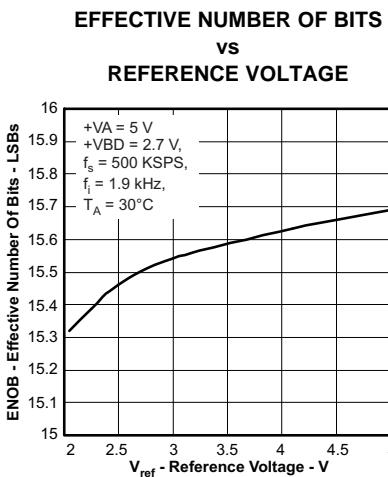
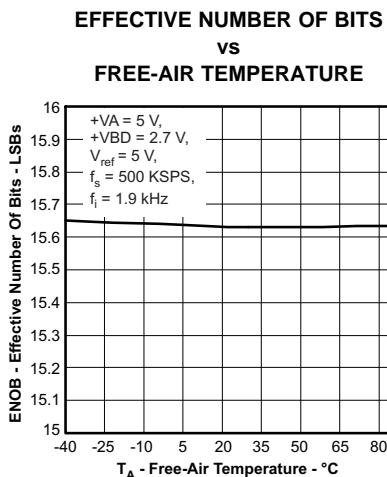
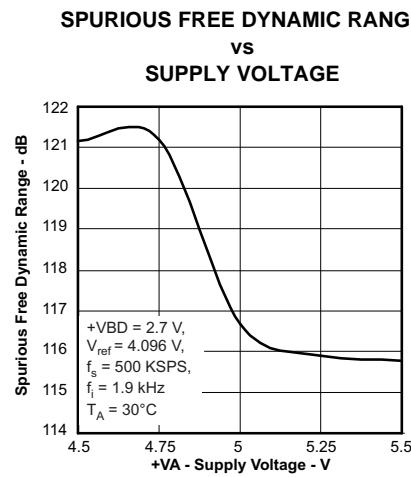
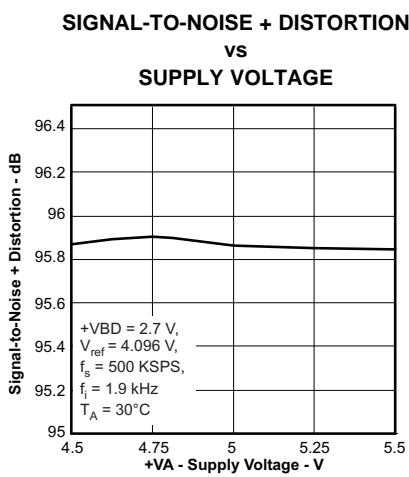
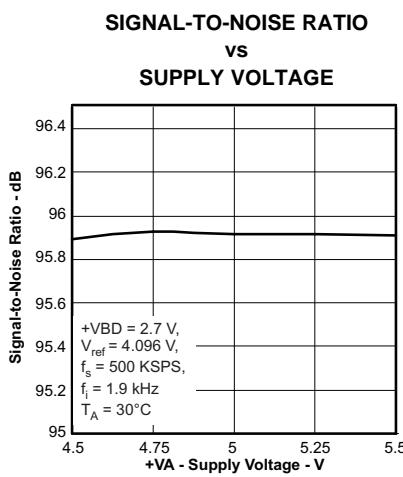
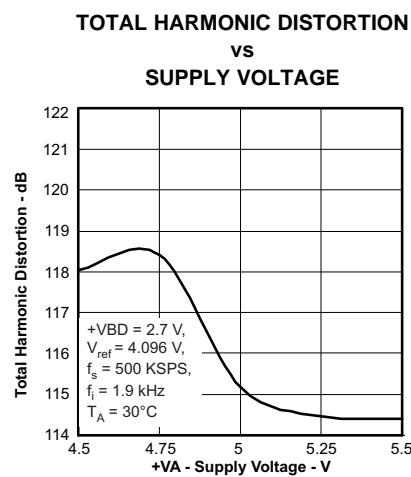


Figure 14.

**TYPICAL CHARACTERISTICS (continued)**

**Figure 15.**

**Figure 16.**

**Figure 17.**

**Figure 18.**

**Figure 19.**

**Figure 20.**

**Figure 21.**

**Figure 22.**

**Figure 23.**

## TYPICAL CHARACTERISTICS (continued)

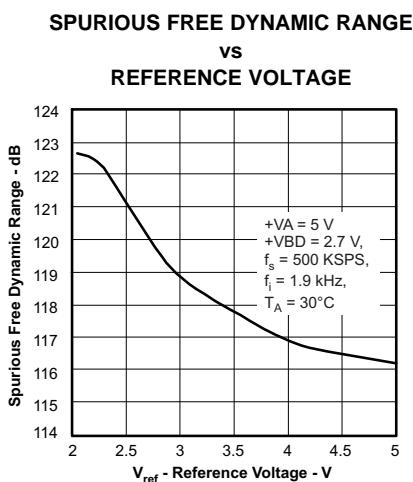


Figure 24.

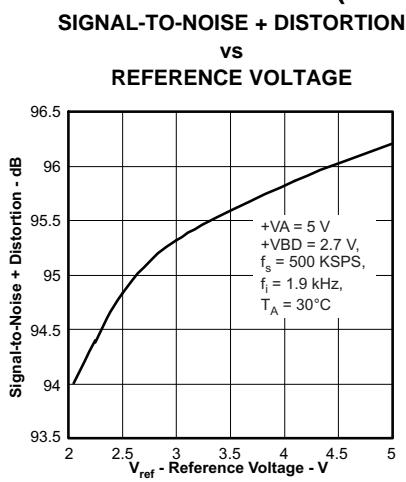


Figure 25.

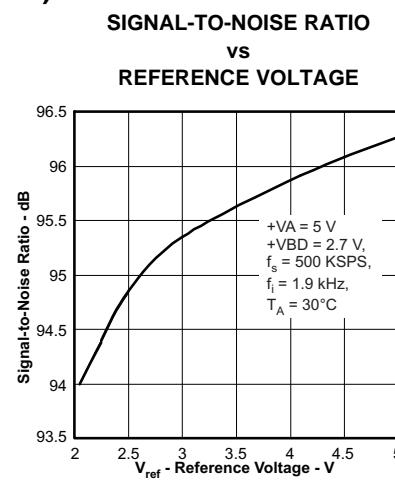


Figure 26.

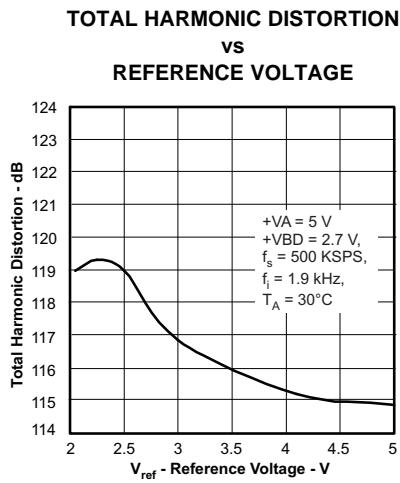


Figure 27.

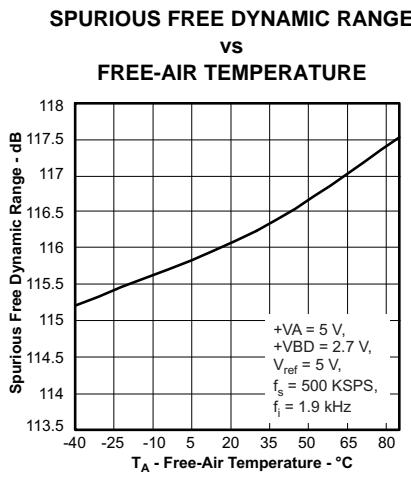


Figure 28.

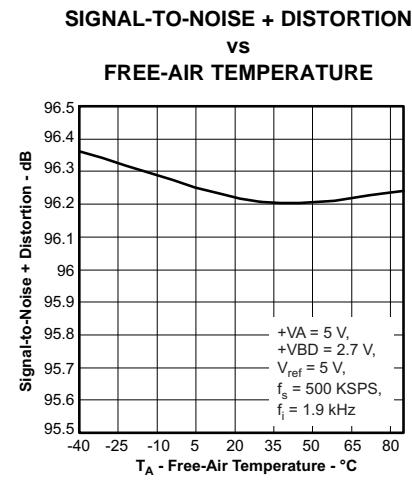


Figure 29.

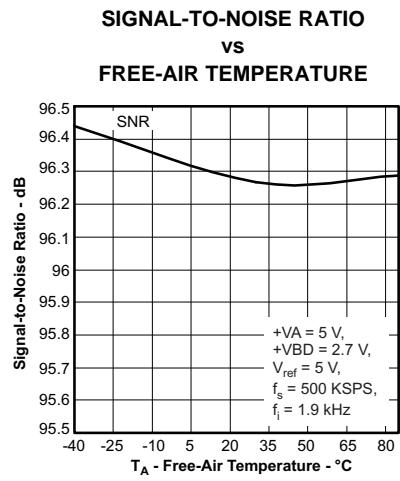


Figure 30.

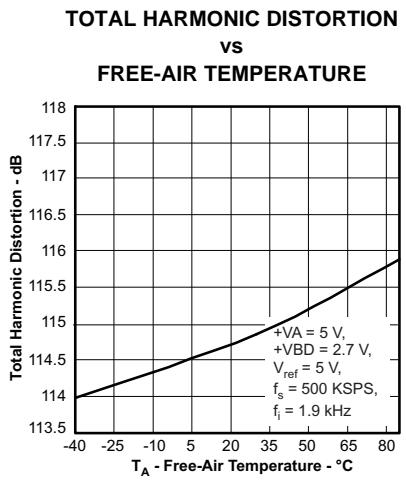


Figure 31.

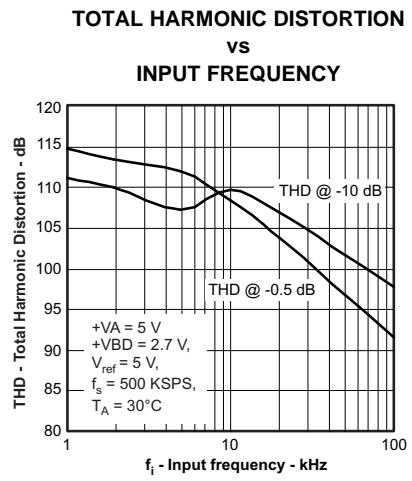
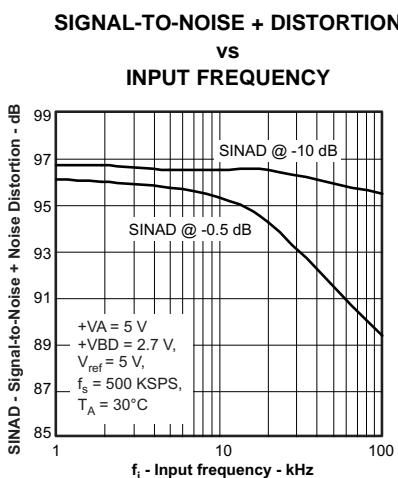
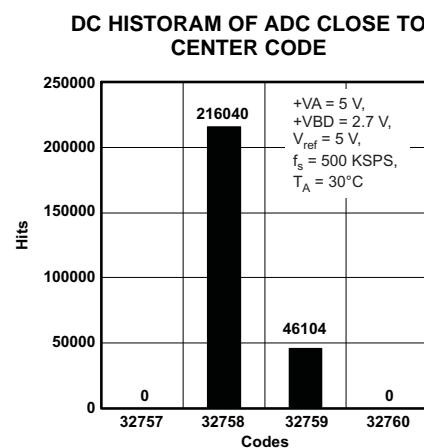
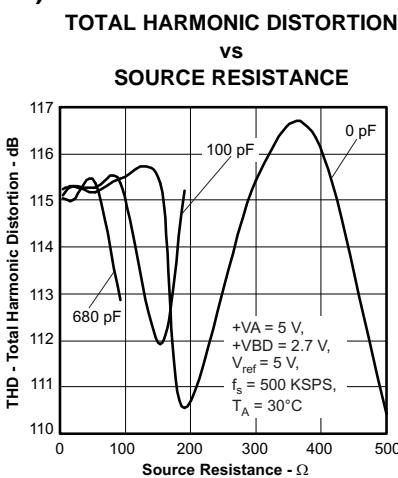
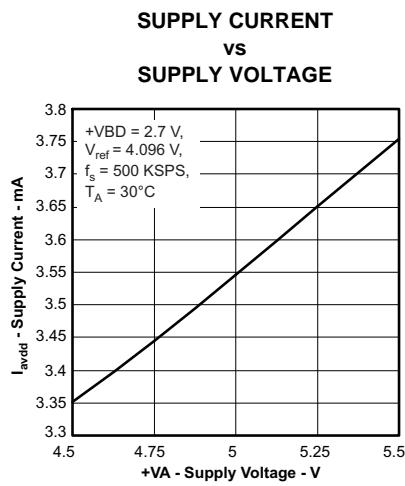
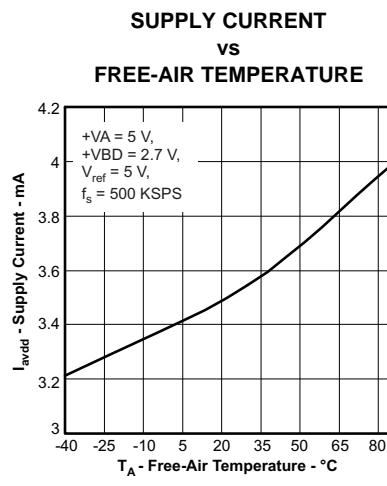
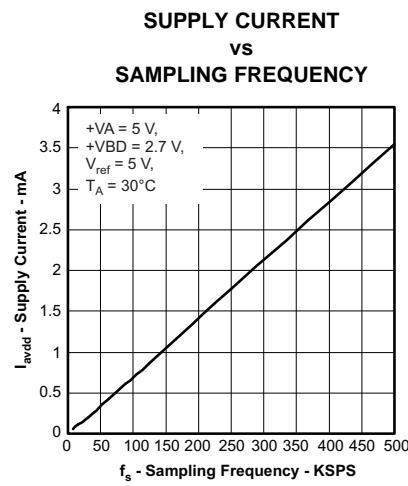
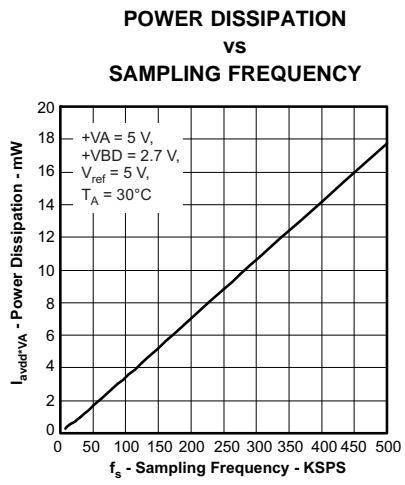
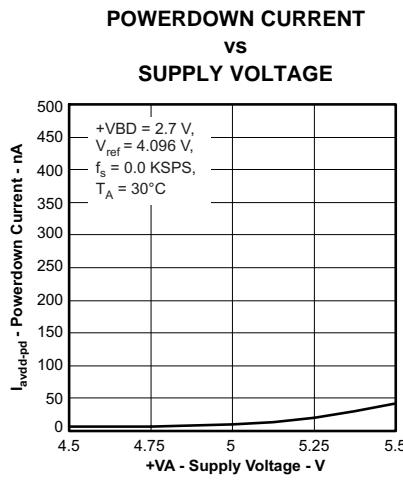
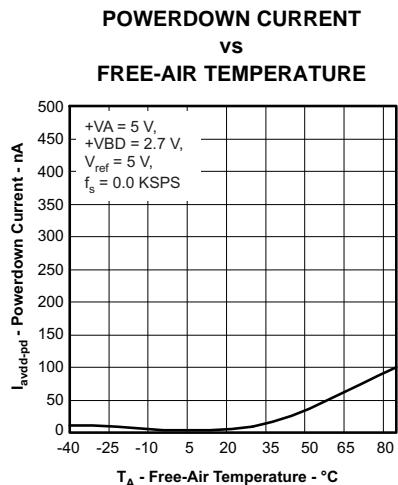


Figure 32.

**TYPICAL CHARACTERISTICS (continued)**

**Figure 33.**

**Figure 34.**

**Figure 35.**

**Figure 36.**

**Figure 37.**

**Figure 38.**

**Figure 39.**

**Figure 40.**

**Figure 41.**

## TYPICAL CHARACTERISTICS (continued)

DNL

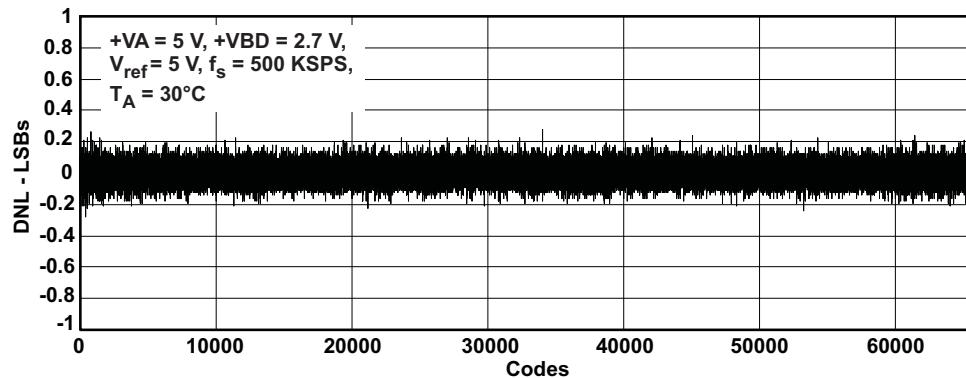


Figure 42.

INL

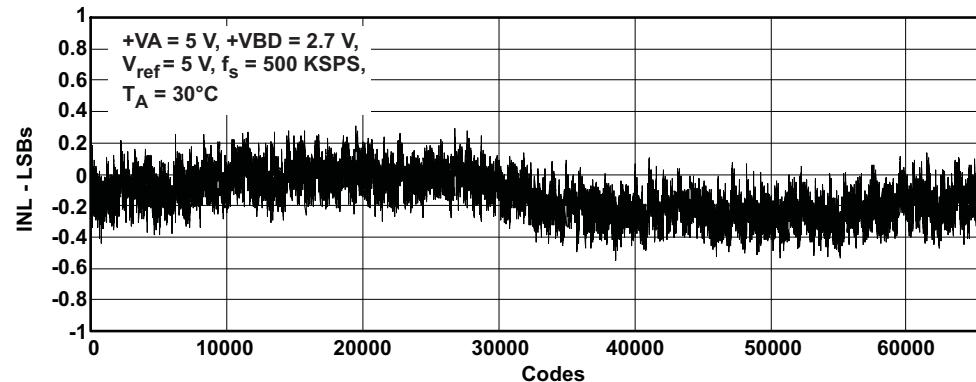


Figure 43.

FFT

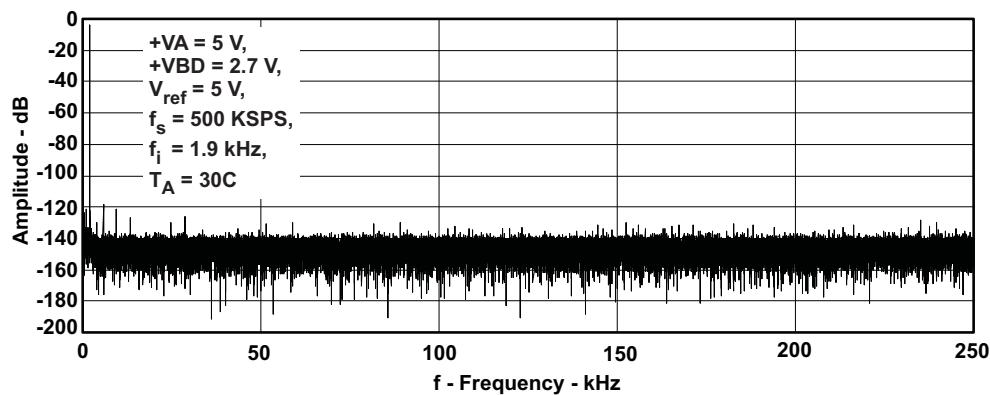


Figure 44.

## DETAILED DESCRIPTIONS AND TIMING DIAGRAMS

The ADS8318 is a high-speed, low power, successive approximation register (SAR) analog-to-digital converter (ADC) that uses an external reference. The architecture is based on charge redistribution, which inherently includes a sample/hold function.

The ADS8318 is a single channel device. The analog input is provided to two input pins: +IN and -IN. When a conversion is initiated, the differential input on these pins is sampled on the internal capacitor array. While a conversion is in progress, both +IN and -IN inputs are disconnected from any internal function.

The ADS8318 has an internal clock that is used to run the conversion, and hence the conversion requires a fixed amount of time. After a conversion is completed, the device reconnects the sampling capacitors to the +IN and -IN pins, and the device is in the acquisition phase. During this phase the device is powered down and conversion data can be read.

The device digital output is available in SPI compatible format. It easily interfaces with microprocessors, DSPs, or FPGAs.

This is a low pin count device; however, it offers six different options for the interface. They can be grossly classified as *CS mode* (3- or 4-wire interface) and *daisy chain mode*. In both modes it can either be with or without a *busy indicator*, where the busy indicator is a bit preceding the 16-bit serial data.

The 3-wire *interface CS mode* is useful for applications which need galvanic isolation on-board, where as 4-wire *interface CS mode* makes it easy to control an individual device while having multiple devices on-board. The *daisy chain mode* is provided to hook multiple devices in a chain like a shift register and is useful to reduce component count and the number signal traces on the board.

### CS MODE

*CS Mode* is selected if SDI is high at the rising edge of CONVST. As indicated before there are four different interface options available in this mode, namely 3-wire *CS mode without busy indicator*, 3-wire *CS mode with busy indicator*, 4-wire *CS mode without busy indicator*, 4-wire *CS mode with busy indicator*. The following section discusses these interface options in detail.

#### 3-Wire CS Mode Without Busy Indicator

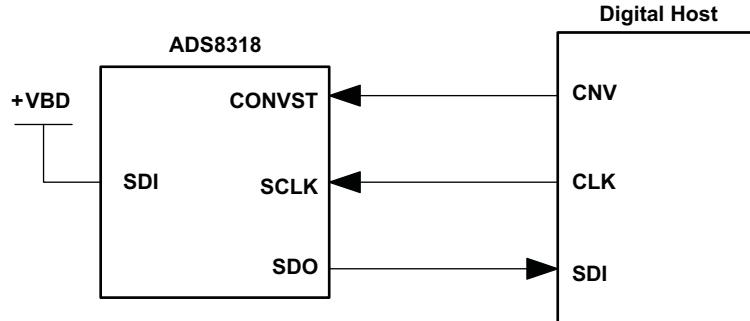


Figure 45. Connection Diagram, 3-Wire CS Mode without Busy Indicator (SDI = 1)

The three wire interface option in *CS mode* is selected if SDI is tied to +VBD (see [Figure 45](#)). In the three wire interface option, CONVST acts like CS. As shown in [Figure 46](#), the device samples the input signal and enters the conversion phase on the rising edge of CONVST, at the same time SDO goes to 3-state. Conversion is done with the internal clock and it continues irrespective of the state of CONVST. As a result it is possible to bring CONVST (acting as CS) low after the start of the conversion to select other devices on the board. But it is absolutely necessary that CONVST is high again before the minimum conversion time ( $t_{cnv}$  in timing requirements table) is elapsed. A high level on CONVST at the end of the conversion ensures the device does not generate a busy indicator.

When the conversion is over, the device enters the acquisition phase and powers down. On the falling edge of CONVST, SDO comes out of three state, and the device outputs the MSB of the data. After this, the device outputs the next lower data bits on every falling edge of SCLK. SDO goes to 3-state after the 16<sup>th</sup> falling edge of SCLK or CONVST high, whichever occurs first. It is necessary that the device sees a minimum of 15 falling edges of SCLK during the low period of CONVST.

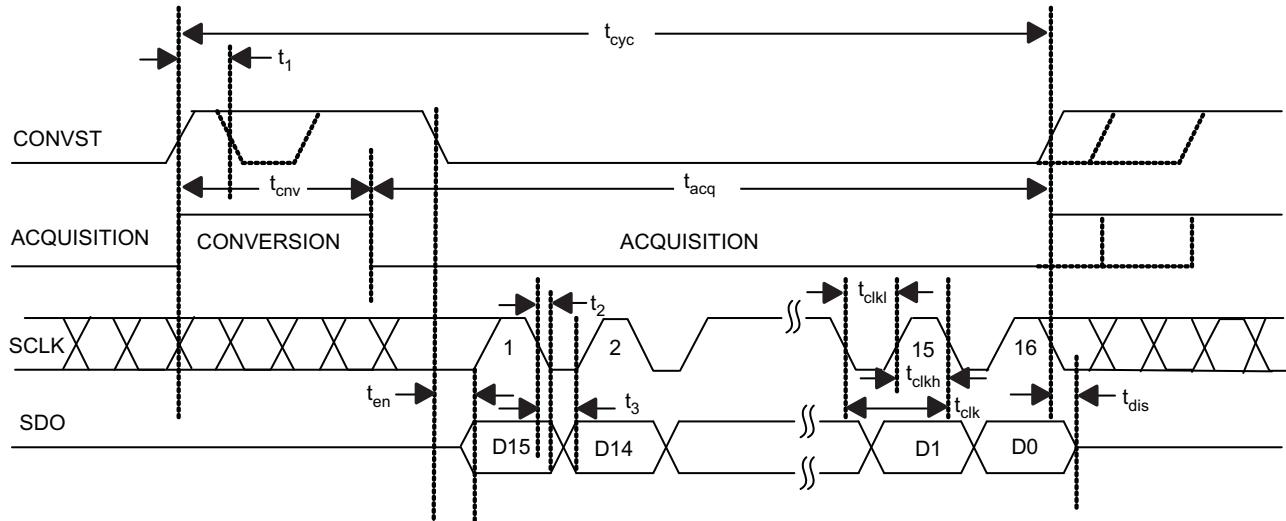


Figure 46. Interface Timing Diagram, 3 Wire  $\overline{\text{CS}}$  Mode Without Busy Indicator (SDI = 1)

### 3 Wire $\overline{\text{CS}}$ Mode With Busy Indicator

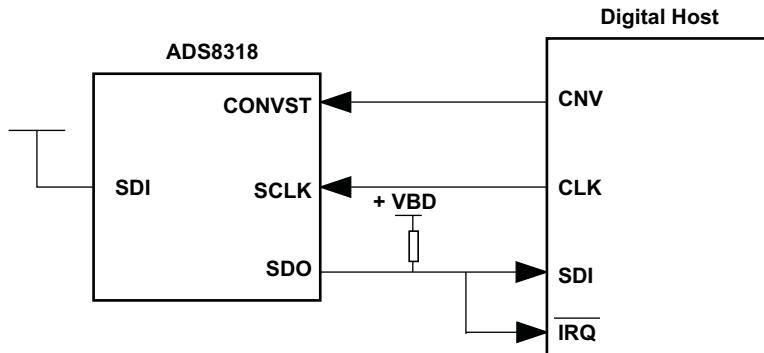
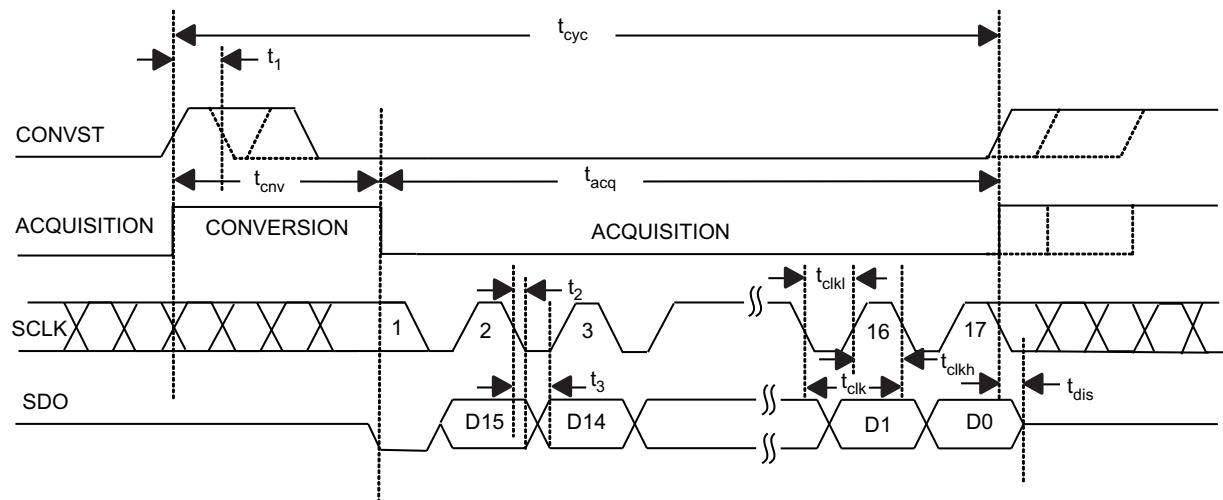


Figure 47. Connection Diagram, 3 Wire  $\overline{\text{CS}}$  Mode With Busy Indicator

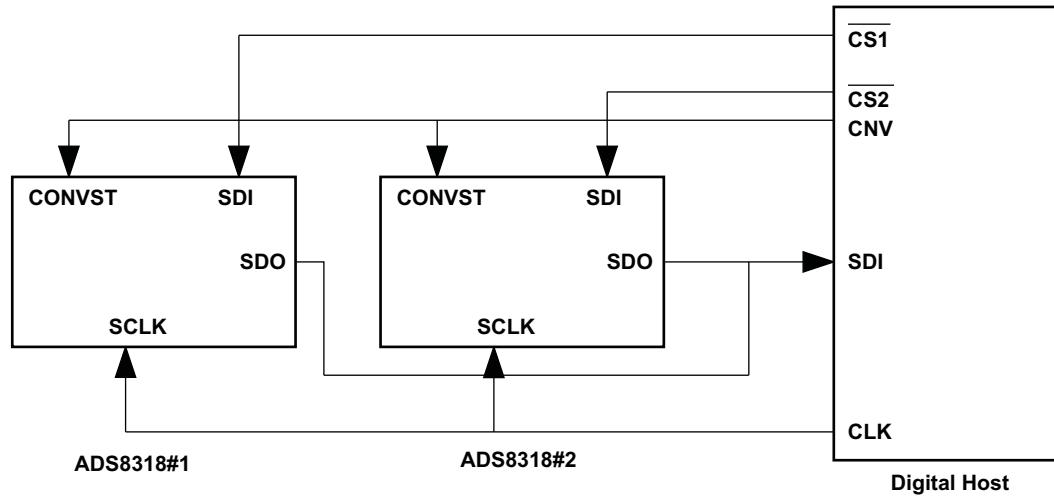
The three wire interface option in  $\overline{\text{CS}}$  mode is selected if SDI is tied to +VBD (see [Figure 47](#)). In the three wire interface option, CONVST acts like  $\overline{\text{CS}}$ . As shown in [Figure 48](#), the device samples the input signal and enters the conversion phase on the rising edge of CONVST, at the same time SDO goes to 3 state. Conversion is done with the internal clock and it continues irrespective of the state of CONVST. As a result it is possible to toggle CONVST (acting as  $\overline{\text{CS}}$ ) after the start of the conversion to select other devices on the board. But it is absolutely necessary that CONVST is low again before the minimum conversion time ( $t_{\text{cnv}}$  in timing requirements table) is elapsed and continues to stay low until the end of maximum conversion time. A low level on the CONVST input at the end of a conversion ensures the device generates a busy indicator.

When the conversion is over, the device enters the acquisition phase and powers down, and the device forces SDO out of three state and outputs a busy indicator bit (low level). The device outputs the MSB of data on the first falling edge of SCLK after the conversion is over and continues to output the next lower data bits on every subsequent falling edge of SCLK. SDO goes to three state after the 17<sup>th</sup> falling edge of SCLK or CONVST high, whichever occurs first. It is necessary that the device sees a minimum of 16 falling edges of SCLK during the low period of CONVST.



**Figure 48. Interface Timing Diagram, 3 Wire  $\overline{\text{CS}}$  Mode With Busy Indicator (SDI = 1)**

#### 4 Wire $\overline{\text{CS}}$ Mode Without Busy Indicator



**Figure 49. Connection Diagram, 4 Wire  $\overline{\text{CS}}$  Mode Without Busy Indicator**

As mentioned before for selecting  $\overline{\text{CS}}$  mode it is necessary that SDI is high at the time of the CONVST rising edge. Unlike in *three wire interface option*, SDI is controlled by digital host and acts like  $\overline{\text{CS}}$ . As shown in [Figure 50](#), SDI goes to a high level before the rising edge of CONVST. The rising edge of CONVST while SDI is high selects CS mode, forces SDO to three state, samples the input signal, and the device enters the conversion phase. In the 4 wire interface option CONVST needs to be at a high level from the start of the conversion until all of the data bits are read. Conversion is done with the internal clock and it continues irrespective of the state of SDI. As a result it is possible to bring SDI (acting as CS) low to select other devices on the board. But it is absolutely necessary that SDI is high again before the minimum conversion time ( $t_{\text{cnv}}$  in timing requirements table) is elapsed.

When the conversion is over, the device enters the acquisition phase and powers down. SDI falling edge can occur after the maximum conversion time ( $t_{\text{cnv}}$  in timing requirements table). Note that it is necessary that SDI is high at the end of the conversion, so that the device does not generate a *busy indicator*. The falling edge of SDI

brings SDO out of 3-state and the device outputs the MSB of the data. Subsequent to this the device outputs the next lower data bits on every falling edge of SCLK. SDO goes to three state after the 16<sup>th</sup> falling edge of SCLK or SDI (CS) high, whichever occurs first. As shown in Figure 49, it is possible to hook multiple devices on the same data bus. In this case the second device SDI (acting as CS) can go low after the first device data is read and device 1 SDO is in three state.

Care needs to be taken so that CONVST and SDI are not low together at any time during the cycle.

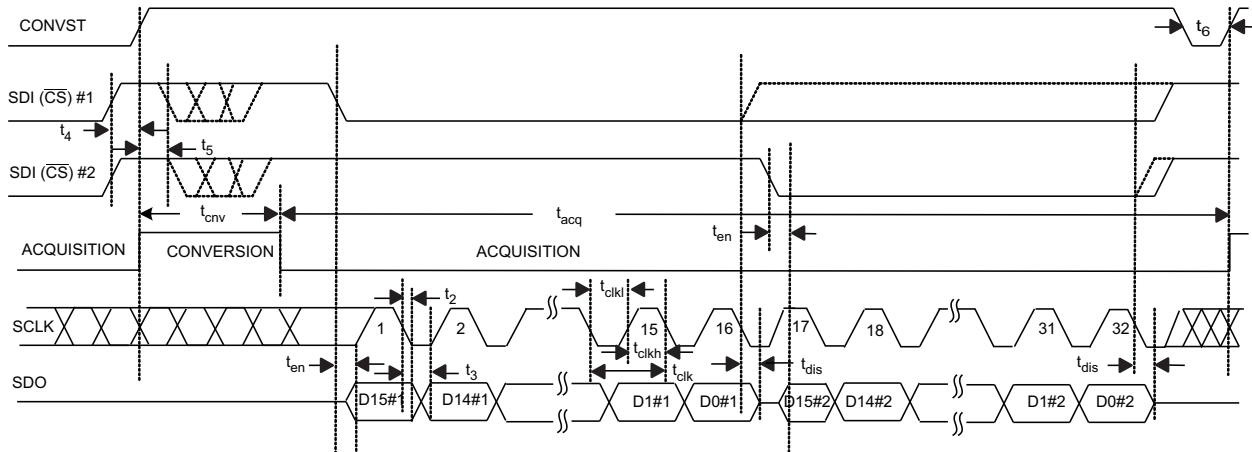


Figure 50. Interface Timing Diagram, 4 Wire CS Mode Without Busy Indicator

#### 4 Wire CS Mode With Busy Indicator

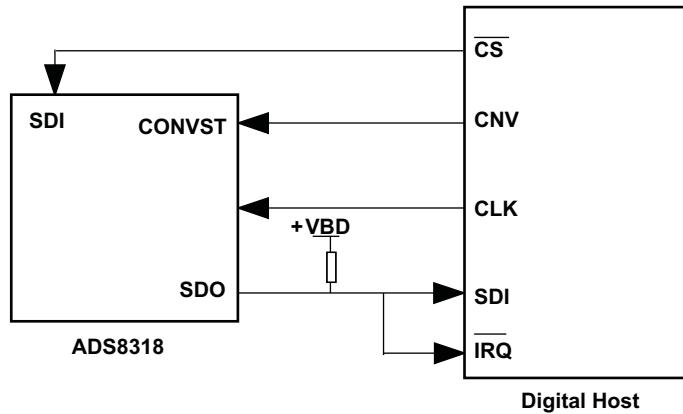
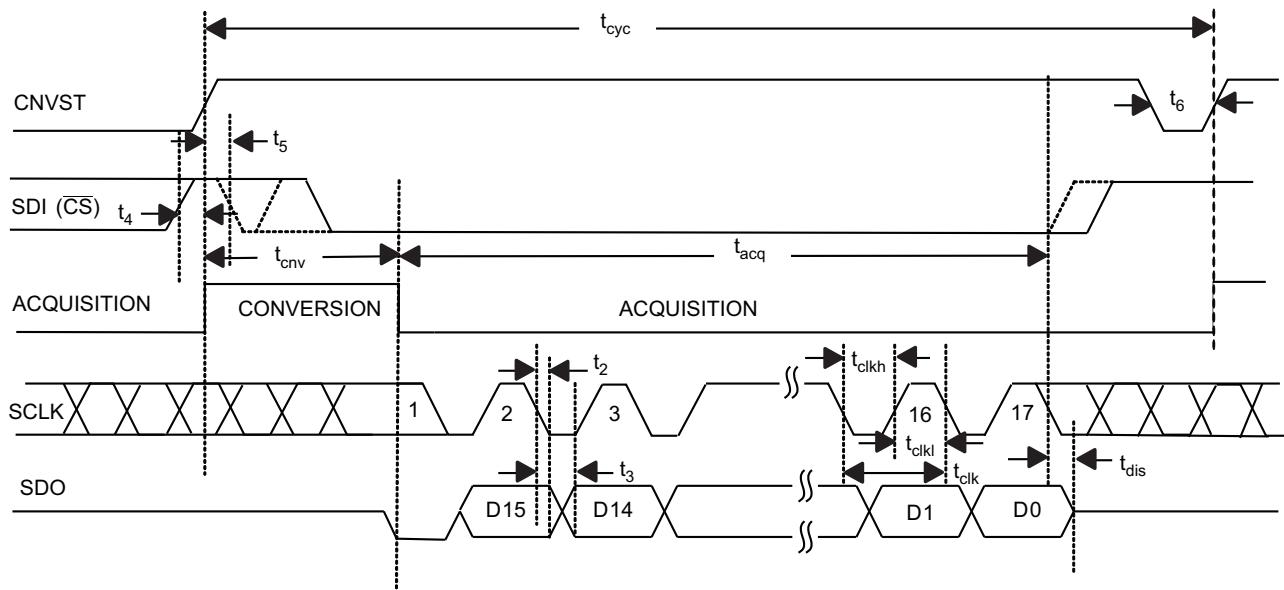


Figure 51. Connection Diagram, 4 Wire CS Mode With Busy Indicator

As mentioned before for selecting CS mode it is necessary that SDI is high at the time of the CONVST rising edge. Unlike in the three wire interface option, SDI is controlled by the digital host and acts like CS. As shown in Figure 52, SDI goes to a high level before the rising edge of CONVST. The rising edge of CONVST while SDI is high selects CS mode, forces SDO to three state, samples the input signal, and the device enters the conversion phase. In the 4 wire interface option CONVST needs to be at a high level from the start of the conversion until all of the data bits are read. Conversion is done with the internal clock and it continues irrespective of the state of SDI. As a result it is possible to toggle SDI (acting as CS) to select other devices on the board. But it is absolutely necessary that SDI is low before the minimum conversion time (t<sub>cnv</sub> in timing requirements table) is elapsed and continues to stay low until the end of the maximum conversion time. A low level on the SDI input at the end of a conversion ensures the device generates a busy indicator.

When the conversion is over, the device enters the acquisition phase and powers down, forces SDO out of three state, and outputs a busy indicator bit (low level). The device outputs the MSB of the data on the first falling edge of SCLK after the conversion is over and continues to output the next lower data bits on every falling edge of SCLK. SDO goes to three state after the 17<sup>th</sup> falling edge of SCLK or SDI (CS) high, whichever occurs first.

Care needs to be taken so that CONVST and SDI are not low together at any time during the cycle.



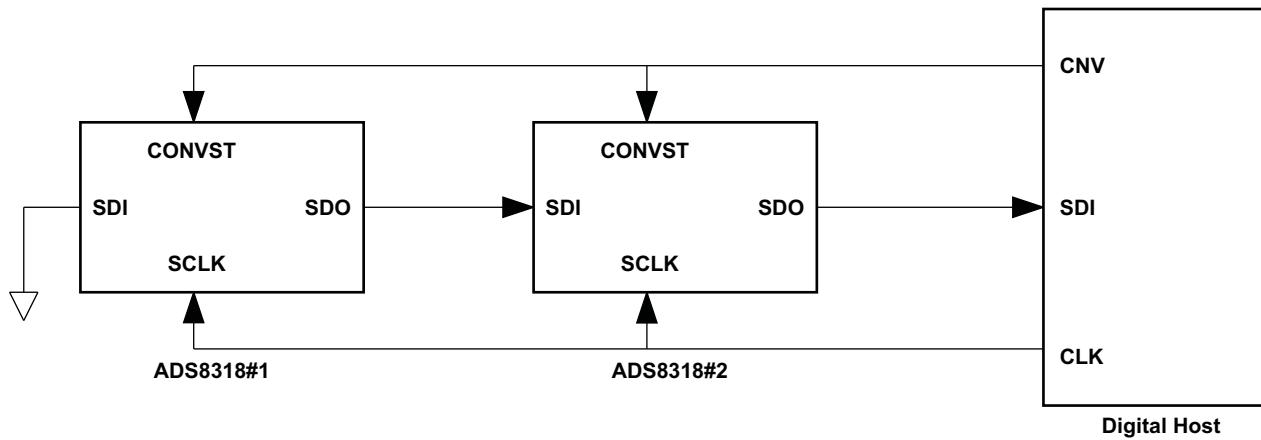
**Figure 52. Interface Timing Diagram, 4 Wire  $\overline{CS}$  Mode With Busy Indicator**

### Daisy Chain Mode

Daisy chain mode is selected if SDI is low at the time of CONVST rising edge. This mode is useful to reduce wiring and hardware like digital isolators in the applications where multiple (ADC) devices are used. In this mode all of the devices are connected in a chain (SDO of one device connected to the SDI of the next device) and data transfer is analogous to a shift register.

Like  $\overline{CS}$  mode even this mode offers operation with or without a busy indicator. The following section discusses these interface options in detail.

### Daisy Chain Mode Without Busy Indicator



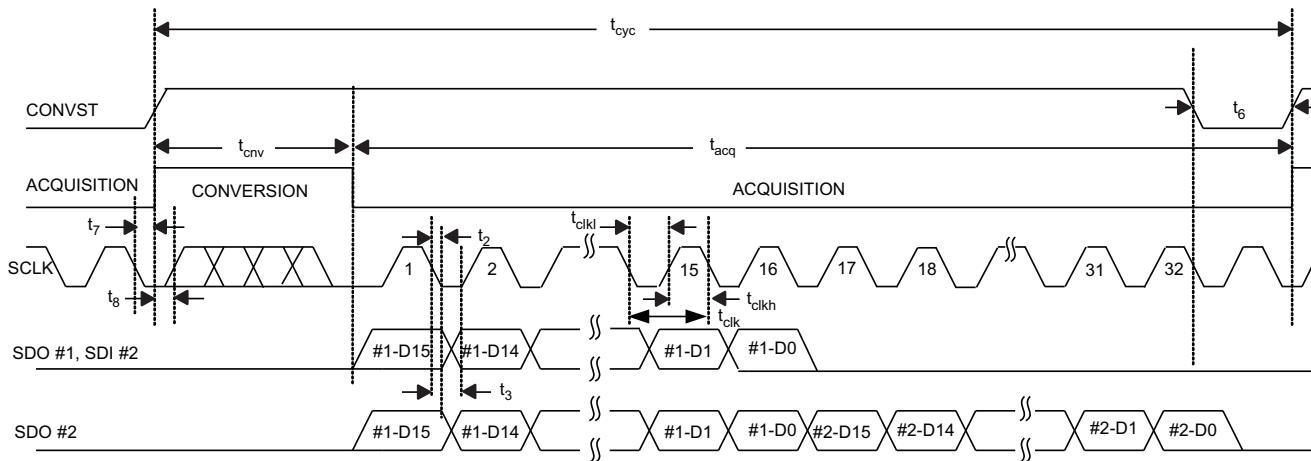
**Figure 53. Connection Diagram, Daisy Chain Mode Without Busy Indicator (SDI = 0)**

Refer to [Figure 53](#) for the connection diagram. SDI for device 1 is tied to ground and SDO of device 1 goes to SDI of device 2 and so on. SDO of the last device in the chain goes to the digital host. CONVST for all of the devices in the chain are tied together. In this mode there is no  $\overline{CS}$  signal. The device SDO is driven low when

SDI and CONVST are low together. The rising edge of CONVST while SDI is low selects daisy chain mode and the device samples the analog input and enters the conversion phase. It is necessary that SCLK is low at the rising edge of CONVST so that the device does not generate a busy indicator at the end of the conversion. In this mode CONVST continues to be high from the start of the conversion until all of the data bits are read. Once started, conversion continues irrespective of the state of SCLK.

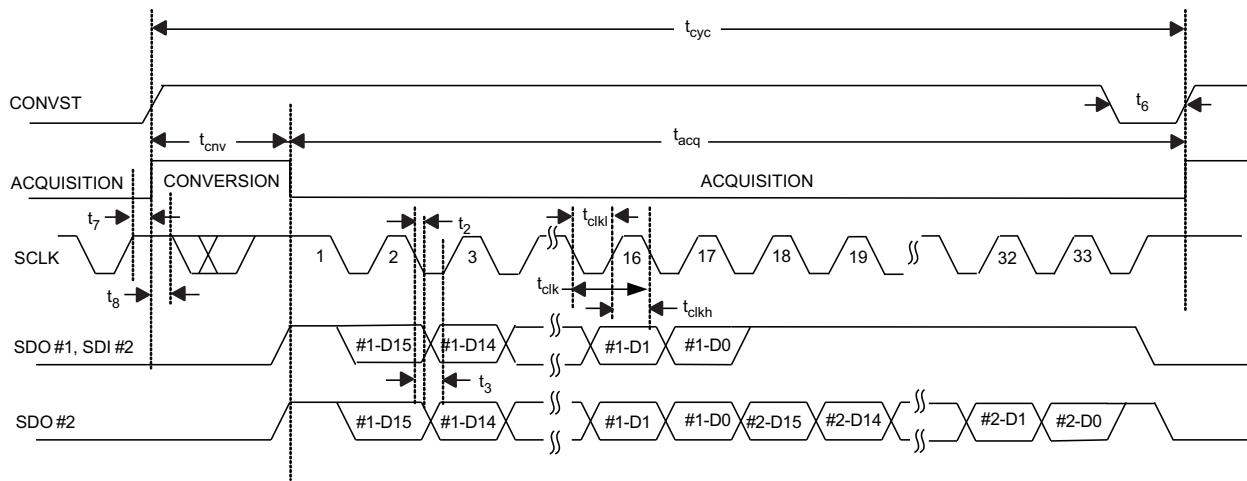
At the end of the conversion, every device in the chain initiates output of its conversion data starting with the MSB bit. Further the next lower data bit is output on every falling edge of SCLK. While every device outputs its data on the SDO pin, it also receives previous device data on the SDI pin (other than device #1) and stores it in the shift register. The device latches incoming data on every falling edge of SCLK. SDO of the first device in the chain goes low after the 16th falling edge of SCLK. All subsequent devices in the chain output the stored data from the previous device in MSB first format immediately following their own data word.

It needs  $16 \times N$  clocks to read data for  $N$  devices in the chain.



and CONVST are wired together, and the setup time of SDI to rising edge of CONVST is adjusted so that the device still enters chain mode even though SDI and CONVST rise together. It is necessary that SCLK is high at the rising edge of CONVST so that the device generates a busy indicator at the end of the conversion. In this mode, CONVST continues to be high from the start of the conversion until all of the data bits are read. Once started, conversion continues irrespective of the state of SCLK.

At the end of the conversion, all the devices in the chain generate busy indicators. On the first falling edge of SCLK following the busy indicator bit, all of the devices in the chain output their conversion data starting with the MSB bit. After this the next lower data bit is output on every falling edge of SCLK. While every device outputs its data on the SDO pin, it also receives the previous device data on the SDI pin (except for device #1) and stores it in the shift register. Each device latches incoming data on every falling edge of SCLK. SDO of the first device in the chain goes high after the 17<sup>th</sup> falling edge of SCLK. All subsequent devices in the chain output the stored data from the previous device in MSB first format immediately following their own data word. It needs  $16 \times N + 1$  clock pulses to read data for N devices in the chain.



**Figure 56. Interface Timing Diagram, Daisy Chain Mode With Busy Indicator**

## APPLICATION INFORMATION

### ANALOG INPUT

When the converter samples the input, the voltage difference between the +IN and -IN inputs is captured on the internal capacitor array. The voltage on the +IN and -IN inputs individually is limited between GND –0.1 V and  $V_{ref}$  + 0.1 V; whereas the differential signal range  $[(+IN) - (-IN)]$  is  $2V_{ref}$  ( $-V_{ref}$  to  $+V_{ref}$ ) with a common mode of  $(V_{ref}/2)$ . This allows the input to reject small signals which are common to both the +IN and -IN inputs.

The (peak) input current through the analog inputs depends upon a number of factors: sample rate, input voltage, and source impedance. The current into the ADS8318 charges the internal capacitor array during the sample period. After this capacitance has been fully charged, there is no further input current. The source of the analog input voltage must be able to charge the input capacitance (59 pF) to a 18-bit settling level within the minimum acquisition time. When the converter goes into hold mode, the input impedance is greater than 1 G $\Omega$ .

Care must be taken regarding the absolute analog input voltage. To maintain linearity of the converter, the +IN and -IN inputs and the span (+IN – (-IN)) should be within the limits specified. Outside of these ranges, converter linearity may not meet specifications.

Care should be taken to ensure that the output impedance of the sources driving the +IN and -IN inputs are matched. If this is not observed, the two inputs could have different settling times. This may result in an offset error, gain error, and linearity error which change with temperature and input voltage.

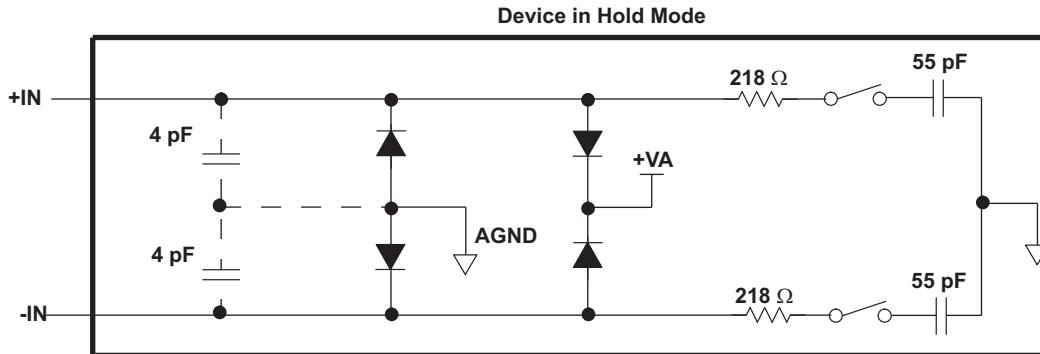


Figure 57. Input Equivalent Circuit

### DRIVER AMPLIFIER CHOICE

The analog input to the converter needs to be driven with a low noise, op-amp like the THS4031, OPA211. An RC filter is recommended at the input pins to low-pass filter the noise from the source. Two resistors of 5 $\Omega$  and a differential capacitor of 1nF is recommended. The input to the converter is a unipolar input voltage in the range 0 V to  $V_{ref}$ . The minimum –3dB bandwidth of the driving operational amplifier can be calculated as:

$$f_{3db} = (\ln(2) \times (n+2)) / (2\pi \times t_{ACQ})$$

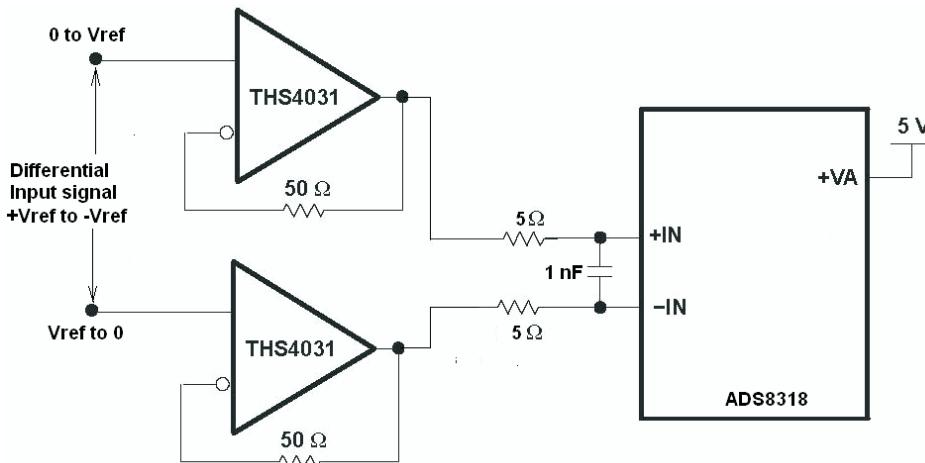
where n is equal to 16, the resolution of the ADC (in the case of the ADS8318). When  $t_{ACQ} = 600$  ns (minimum acquisition time), the minimum bandwidth of the driving circuit is ~3 MHz (including RC following the driver OPA). The bandwidth can be relaxed if the acquisition time is increased by the application.

Typically a low noise OPA with ten times or higher bandwidth is selected. The driving circuit bandwidth is adjusted (to the required value) with a RC following the OPA. The OPA211 or THS4031 from Texas Instruments is recommended for driving high-resolution high-speed ADCs.

### DRIVER AMPLIFIER CONFIGURATIONS

#### Configuration for Unipolar Differential Input

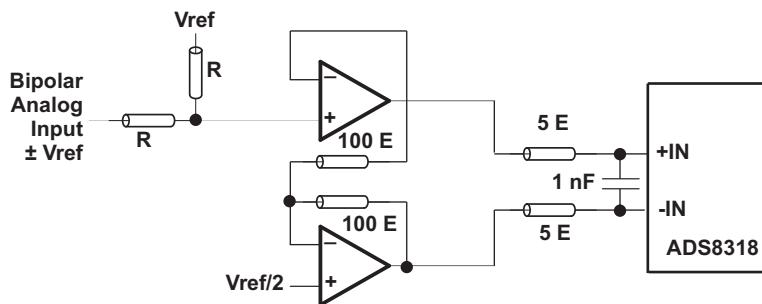
It is better to use a unity gain, noninverting buffer configuration for a unipolar, differential input having a  $\pm V_{ref}$  signal range with  $V_{ref}/2$  common-mode. As explained before a RC following the OPA limits the input circuit bandwidth just enough for 16-bit settling. Note higher bandwidth reduces the settling time (beyond what is needed) but increases the noise in the ADC sampled signal, and hence the ADC output.



**Figure 58. Unipolar Differential Input Drive Configuration**

#### Configuration for Bipolar Single-Ended Input

The following circuit shows a way to convert a single-ended bipolar input to the unipolar differential input needed for the converter. Note that the higher values of the resistors at the input of the top OPA may reduce power consumption of the circuit but increase noise in the driving circuit. One can choose these components based on application needs.



OPA Shown is THS4031 or OPA211

**Figure 59. Bipolar Single-Ended Input Drive Configuration**

#### REFERENCE

The ADS8318 can operate with an external reference with a range from 2.048 V to  $V_{DD} + 0.1$  V. A clean, low noise, well-decoupled reference voltage on this pin is required to ensure good performance of the converter. A low noise band-gap reference like the REF5050 can be used to drive this pin as shown in [Figure 60](#) and [Figure 61](#). The capacitor should be placed as close as possible to the pins of the device.

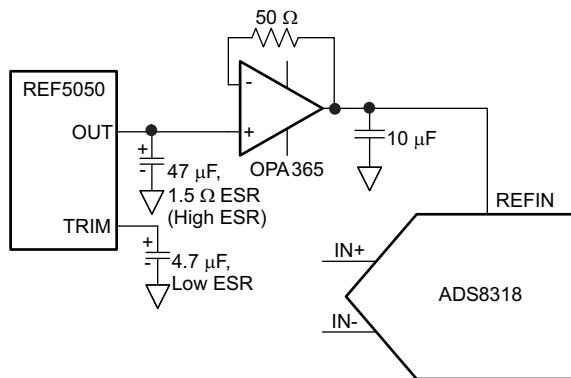


Figure 60. External Reference Driving Circuit

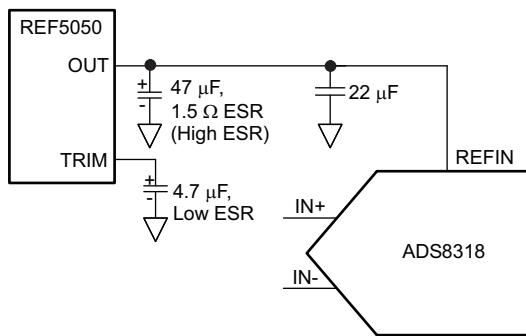


Figure 61. Direct External Reference Driving Circuit

## POWER SAVING

The ADS8318 has an auto power-down feature. The device powers down at the end of every conversion. The input signal is acquired on sampling capacitors while the device is in the power-down state, and at the same time the conversion results are available for reading. The device powers up by itself on the start of the conversion. As discussed before, the conversion runs on an internal clock and takes a fixed time. As a result, device power consumption is directly proportional to the speed of operation.

## DIGITAL OUTPUT

As discussed before (in the *DESCRIPTION* and *TIMING DIAGRAMS* sections) the device digital output is SPI compatible. The following table lists the output codes corresponding to various analog input voltages.

DESCRIPTION	ANALOG VALUE (V)	DIGITAL OUTPUT STRAIGHT BINARY	
Full-scale range	$2^*V_{ref}$		
Least significant bit (LSB)	$2^*V_{ref}/65536$	BINARY CODE	HEX CODE
Positive full scale	$+V_{ref} - 1$ LSB	0111 1111 1111 1111	7FFF
Midscale	0 V	0000 0000 0000 0000	0000
Midscale – 1 LSB	0 – 1 LSB	1111 1111 1111 1111	FFFF
Negative full scale	$-V_{ref}$	1000 0000 0000 0000	8000

## SCLK INPUT

The device uses SCLK for serial data output. Data is read after the conversion is over and the device is in the acquisition phase. It is possible to use a free running SCLK for the device, but it is recommended to stop the clock during a conversion, as the clock edges can couple with the internal analog circuit and can affect conversion results.

## REVISION HISTORY

<b>Changes from Original (May 2008) to Revision A</b>	<b>Page</b>
• Changed Condition in first TIMING REQUIREMENTS from 4.5 V to 3.1 V .....	5
• Changed SCLK Low time MIN value from 9ns to 8ns and SCLK High time MIN value from 9ns to 8ns .....	5
• Changed Condition in second TIMING REQUIREMENTS from +4.5 V to + 3.1 V .....	6

**PACKAGING INFORMATION**

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
<a href="#">ADS8318IBDGSR</a>	Active	Production	VSSOP (DGS)   10	2500   LARGE T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
ADS8318IBDGSR.A	Active	Production	VSSOP (DGS)   10	2500   LARGE T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
<a href="#">ADS8318IBDGST</a>	Active	Production	VSSOP (DGS)   10	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
ADS8318IBDGST.A	Active	Production	VSSOP (DGS)   10	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
<a href="#">ADS8318IBDRCT</a>	Active	Production	VSON (DRC)   10	250   SMALL T&R	Yes	Call TI	Level-3-260C-168 HR	-40 to 85	CBE
ADS8318IBDRCT.A	Active	Production	VSON (DRC)   10	250   SMALL T&R	Yes	Call TI	Level-3-260C-168 HR	-40 to 85	CBE
<a href="#">ADS8318IDGSR</a>	Active	Production	VSSOP (DGS)   10	2500   LARGE T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
ADS8318IDGSR.A	Active	Production	VSSOP (DGS)   10	2500   LARGE T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
<a href="#">ADS8318IDGST</a>	Active	Production	VSSOP (DGS)   10	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
ADS8318IDGST.A	Active	Production	VSSOP (DGS)   10	250   SMALL T&R	Yes	Call TI	Level-2-260C-1 YEAR	-40 to 85	CBC
<a href="#">ADS8318IDRCT</a>	Active	Production	VSON (DRC)   10	250   SMALL T&R	Yes	Call TI	Level-3-260C-168 HR	-40 to 85	CBE
ADS8318IDRCT.A	Active	Production	VSON (DRC)   10	250   SMALL T&R	Yes	Call TI	Level-3-260C-168 HR	-40 to 85	CBE

<sup>(1)</sup> **Status:** For more details on status, see our [product life cycle](#).

<sup>(2)</sup> **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

<sup>(4)</sup> **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

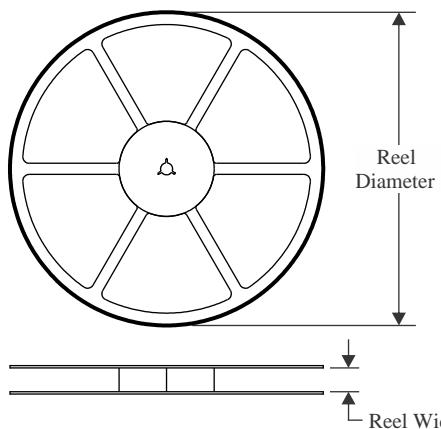
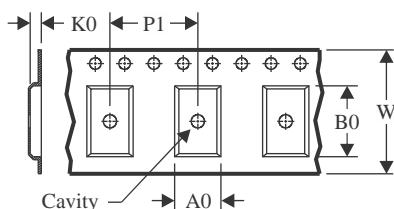
<sup>(6)</sup> **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

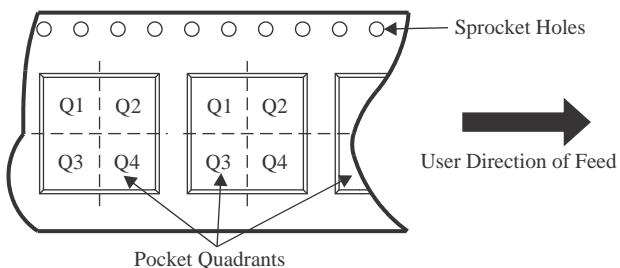
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**TAPE AND REEL INFORMATION**
**REEL DIMENSIONS**

**TAPE DIMENSIONS**


A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

**QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS8318IBDRCT	VSON	DRC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
ADS8318IDRCT	VSON	DRC	10	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2

**TAPE AND REEL BOX DIMENSIONS**


\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADS8318IBDRCT	VSON	DRC	10	250	210.0	185.0	35.0
ADS8318IDRCT	VSON	DRC	10	250	210.0	185.0	35.0

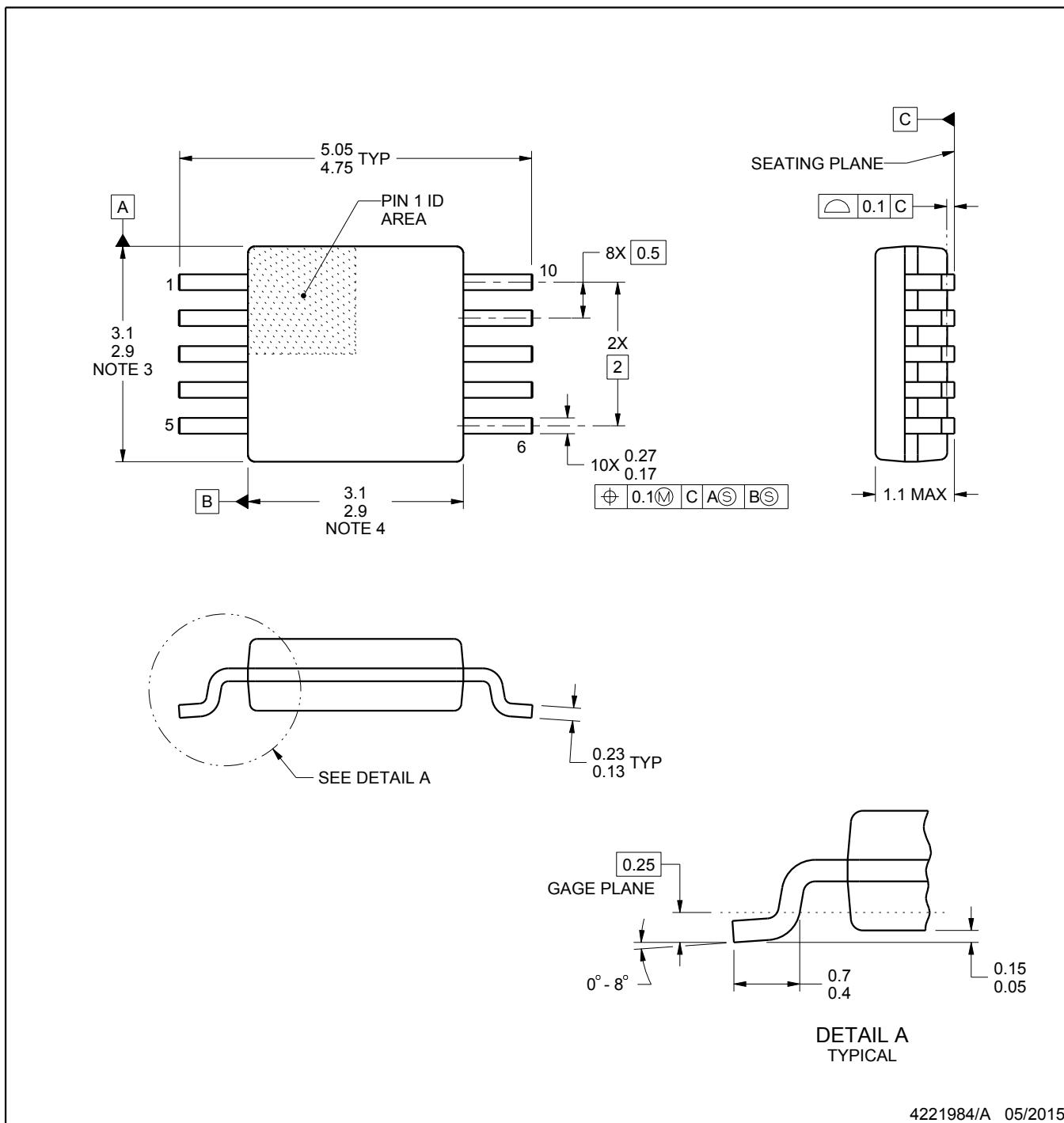
# PACKAGE OUTLINE

DGS0010A



VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



4221984/A 05/2015

## NOTES:

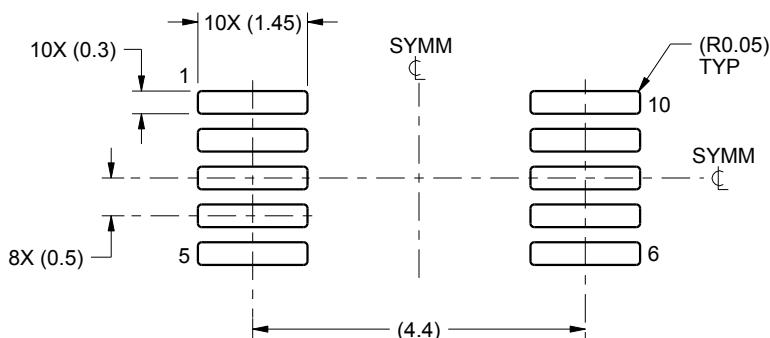
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-187, variation BA.

# EXAMPLE BOARD LAYOUT

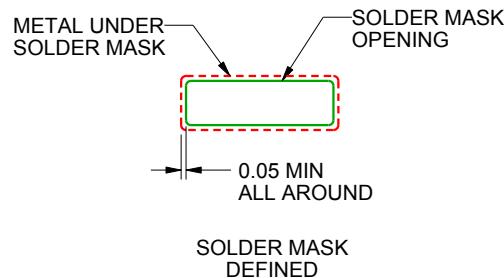
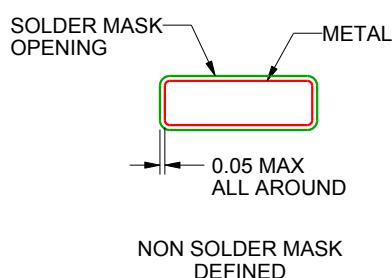
DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE  
SCALE:10X



SOLDER MASK DETAILS  
NOT TO SCALE

4221984/A 05/2015

NOTES: (continued)

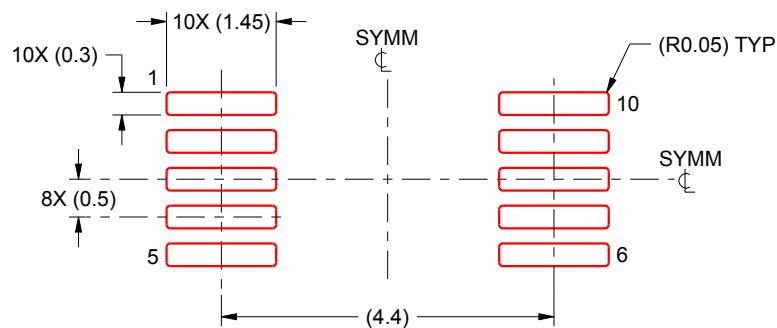
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

# EXAMPLE STENCIL DESIGN

DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE  
BASED ON 0.125 mm THICK STENCIL  
SCALE:10X

4221984/A 05/2015

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

# GENERIC PACKAGE VIEW

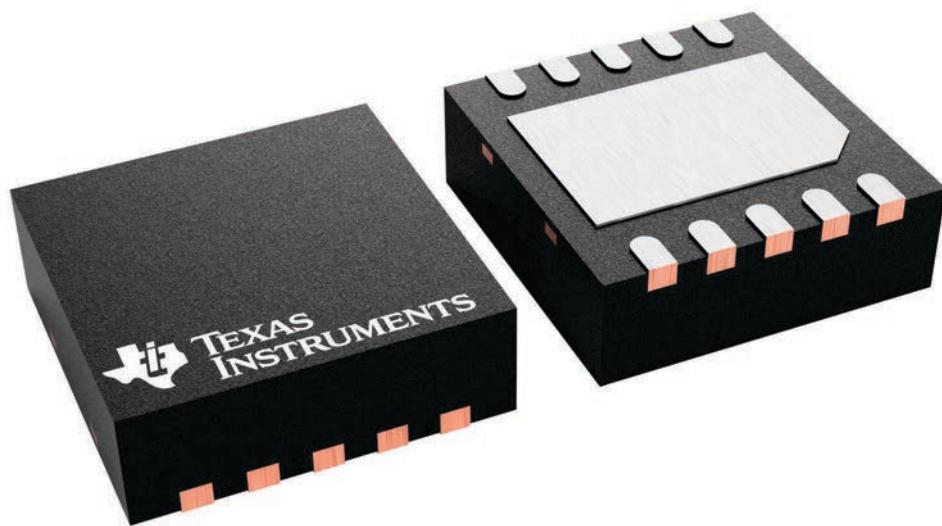
## DRC 10

## VSON - 1 mm max height

3 x 3, 0.5 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary.  
Refer to the product data sheet for package details.

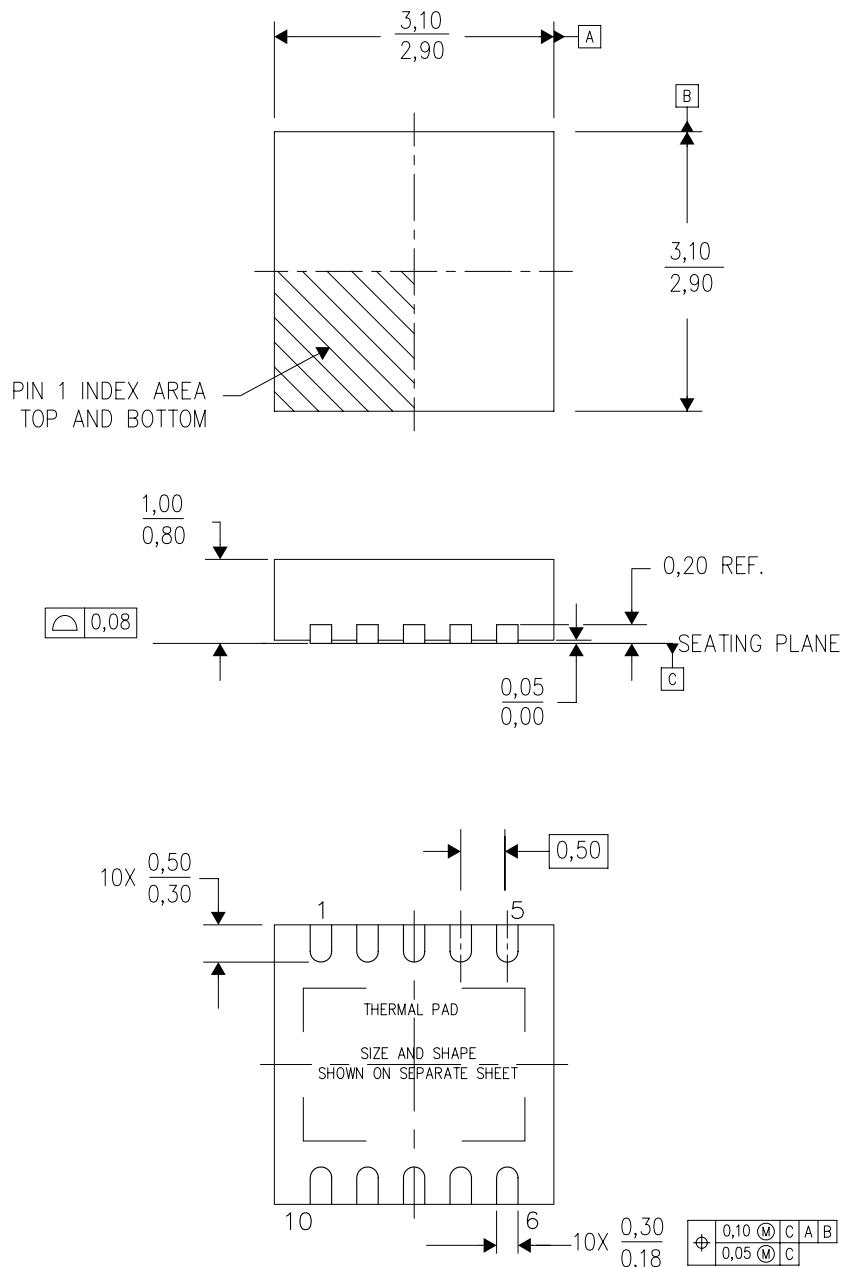


4226193/A

## MECHANICAL DATA

DRC (S-PVSON-N10)

PLASTIC SMALL OUTLINE NO-LEAD



4204102-3/L 09/11

NOTES:

- All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
- This drawing is subject to change without notice.
- Small Outline No-Lead (SON) package configuration.
- The package thermal pad must be soldered to the board for thermal and mechanical performance, if present.
- See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions, if present.

# THERMAL PAD MECHANICAL DATA

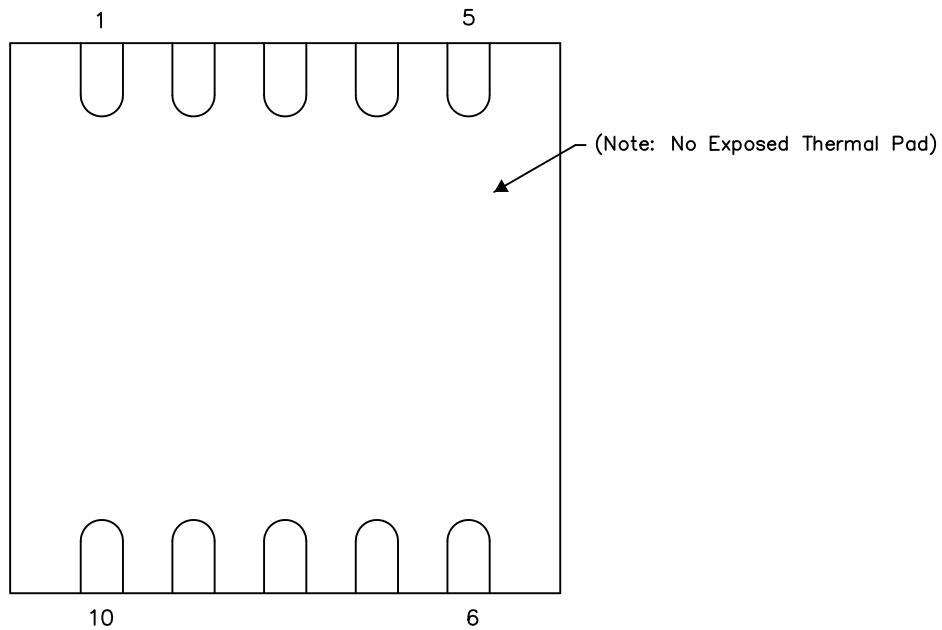
DRC (S-PVSON-N10)

PLASTIC SMALL OUTLINE NO-LEAD

## THERMAL INFORMATION

This version of the package has no exposed thermal pad. This must be accounted for when estimating thermal performance.

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at [www.ti.com](http://www.ti.com).



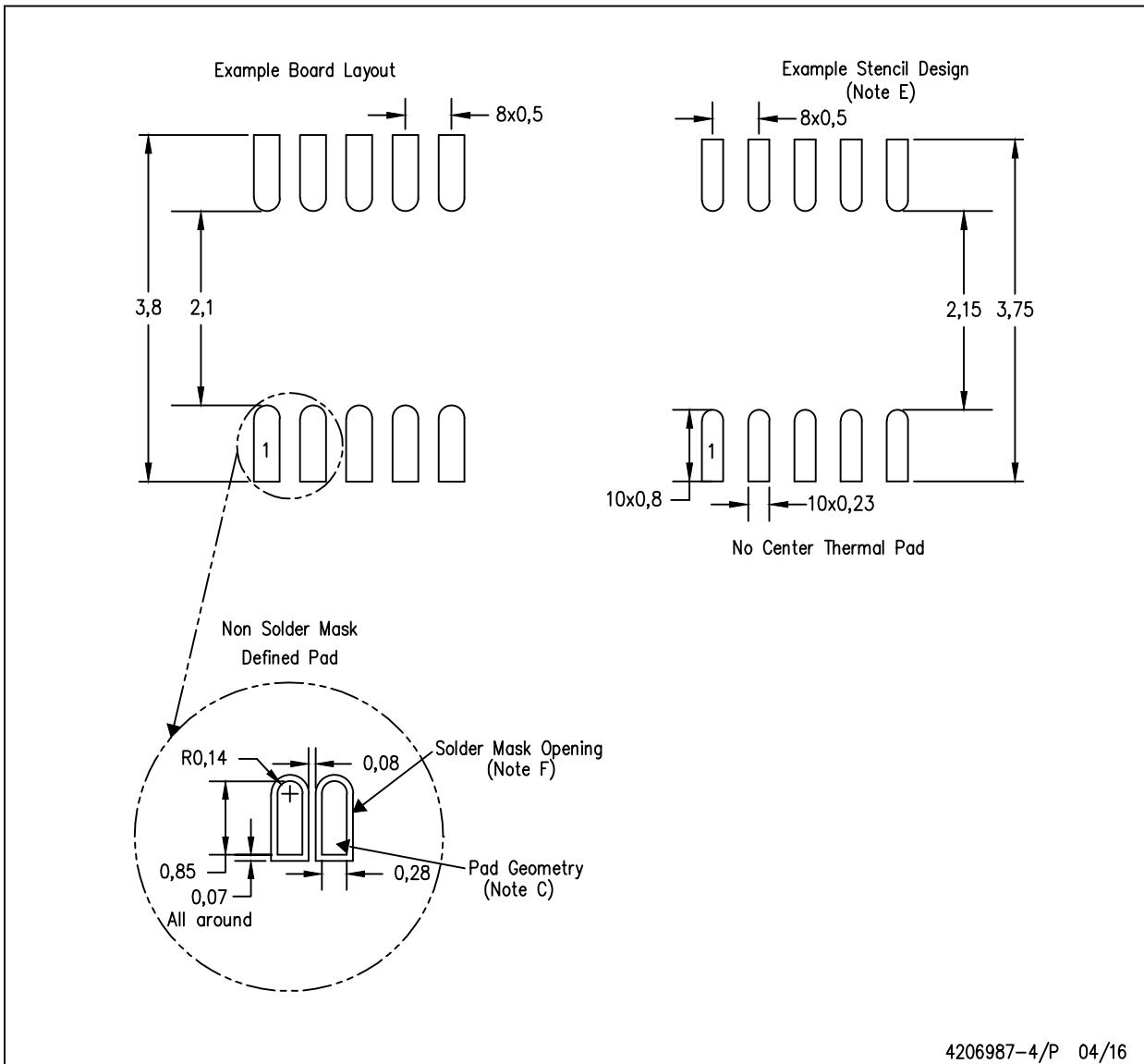
Bottom View

4206565-5/Y 08/15

## LAND PATTERN DATA

DRC (S-PVSON-N10)

PLASTIC SMALL OUTLINE NO-LEAD



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package does not have a center thermal pad. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at [www.ti.com](http://www.ti.com) <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.

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